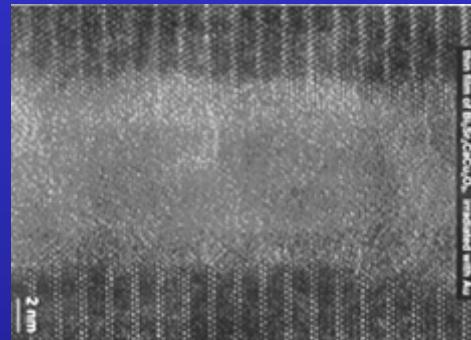


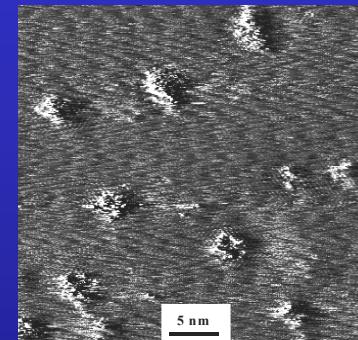
# Materials research with ion beams

## □ beam-induced material modifications

- track formation
- damage analysis
- threshold
- sputtering



single ion track

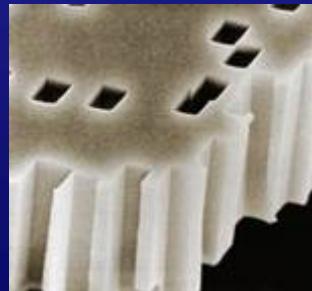


surface tracks



irradiated epoxy foils

## □ nanotechnology



nanopores



biosensors

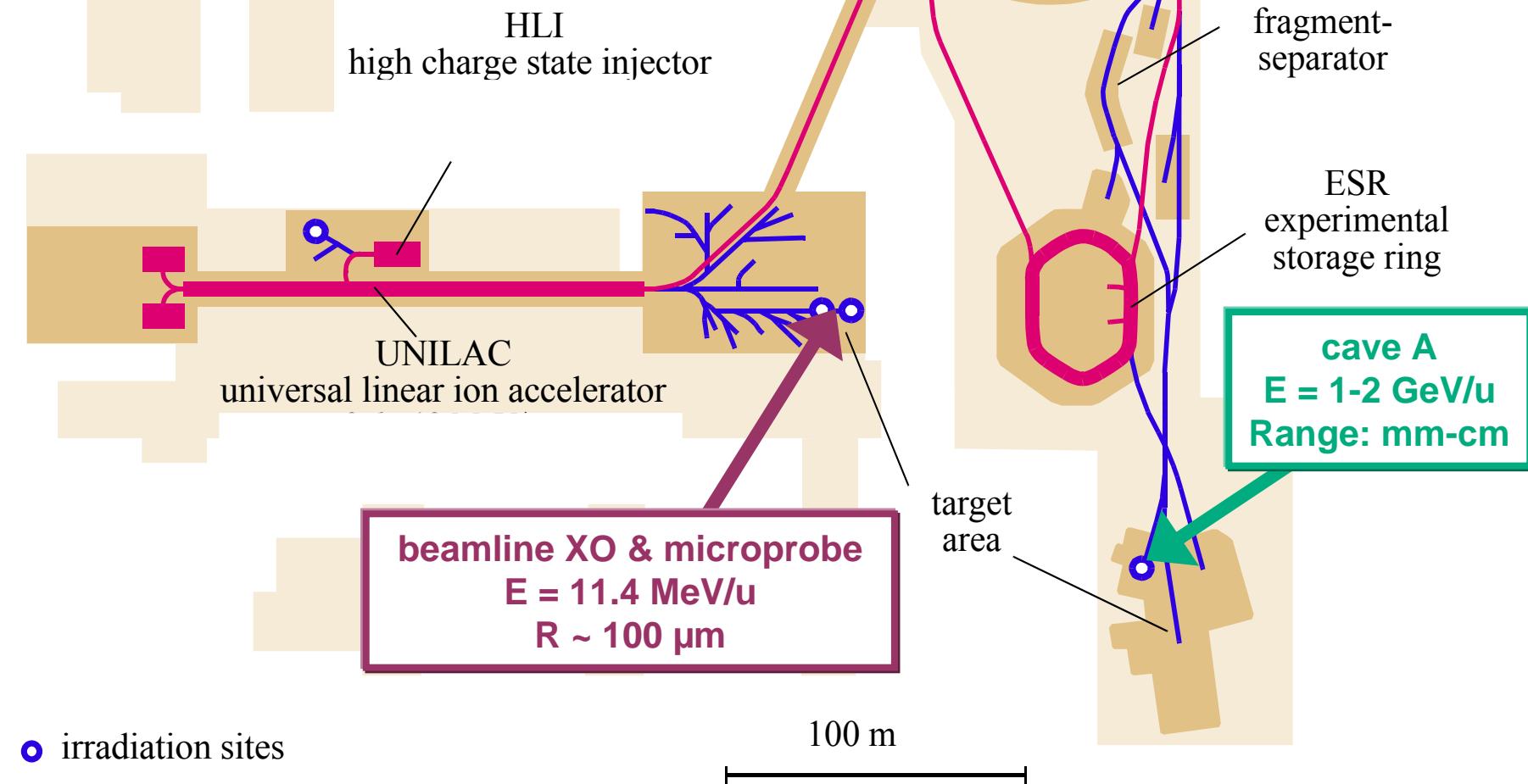


nanowires

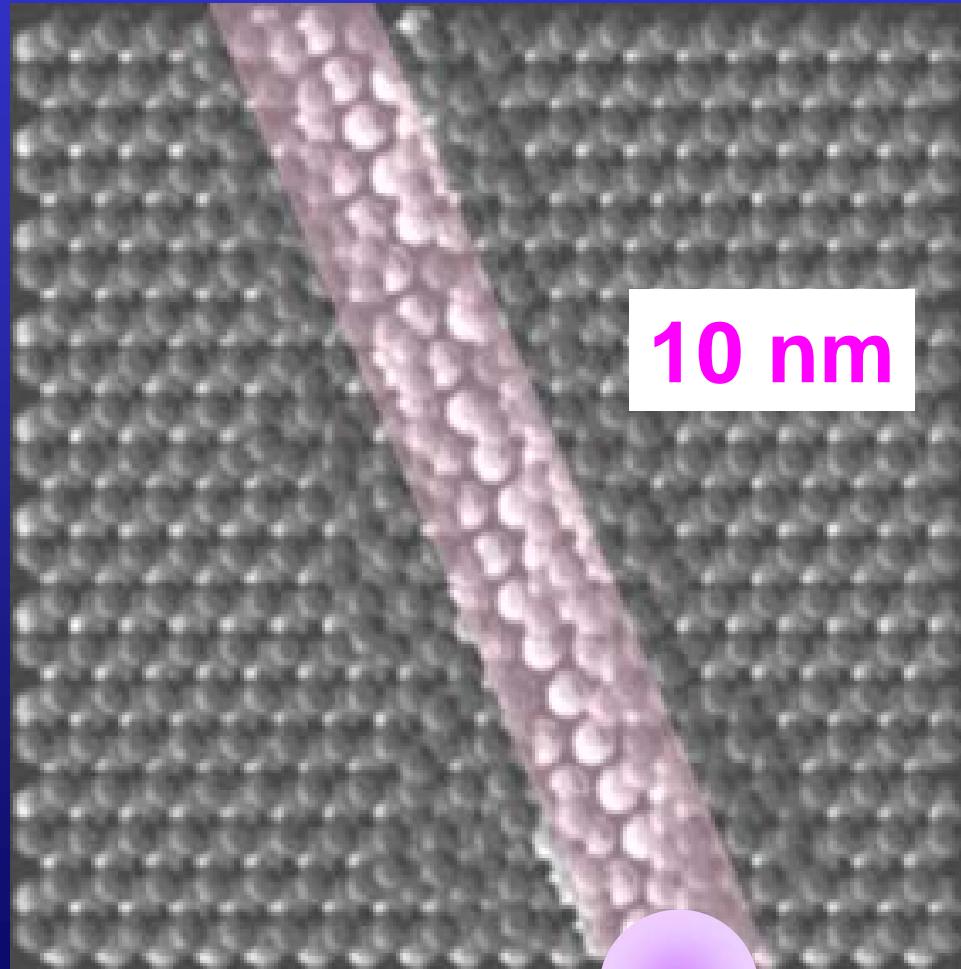
# Irradiation Experiments for Materials Research

ion species ...C...Xe...U

fluence  $1 \dots 10^9 \dots 10^{13}$  ions/cm $^2$

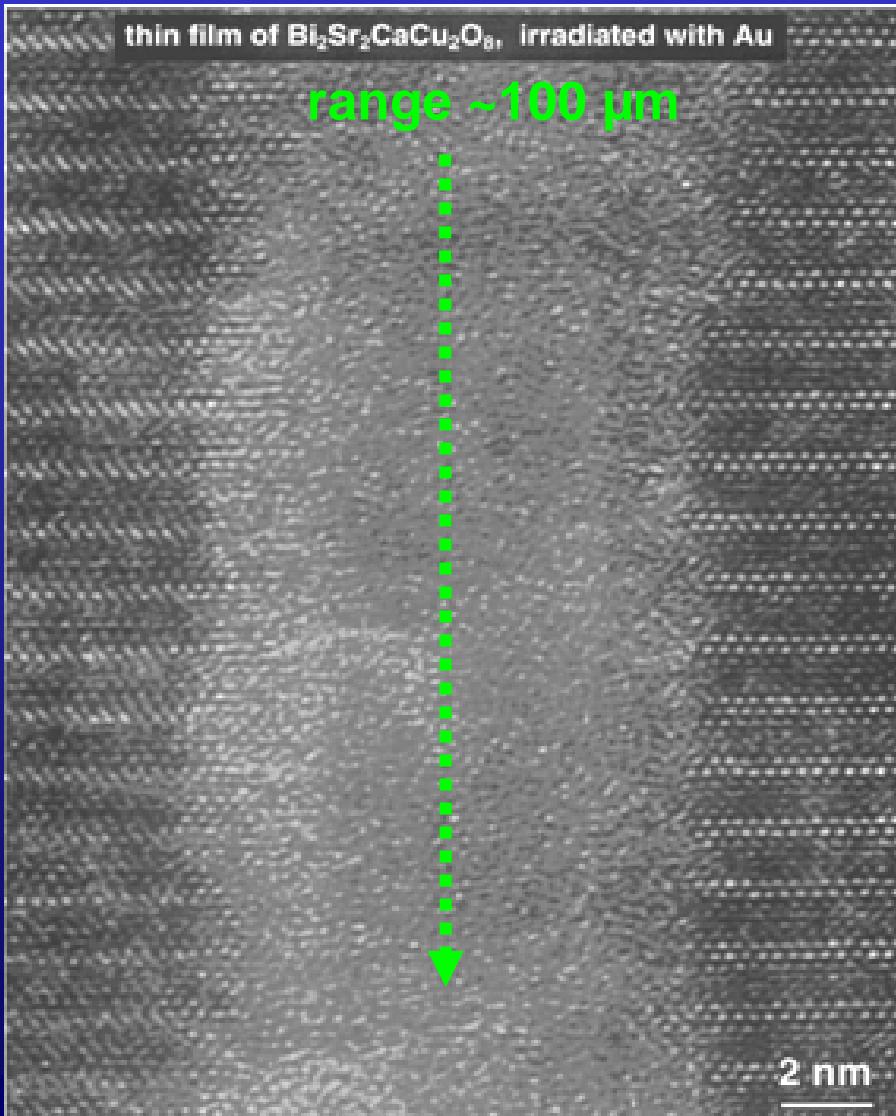


**ion beams**  
kinetic energy: MeV- GeV  
10% of velocity of light

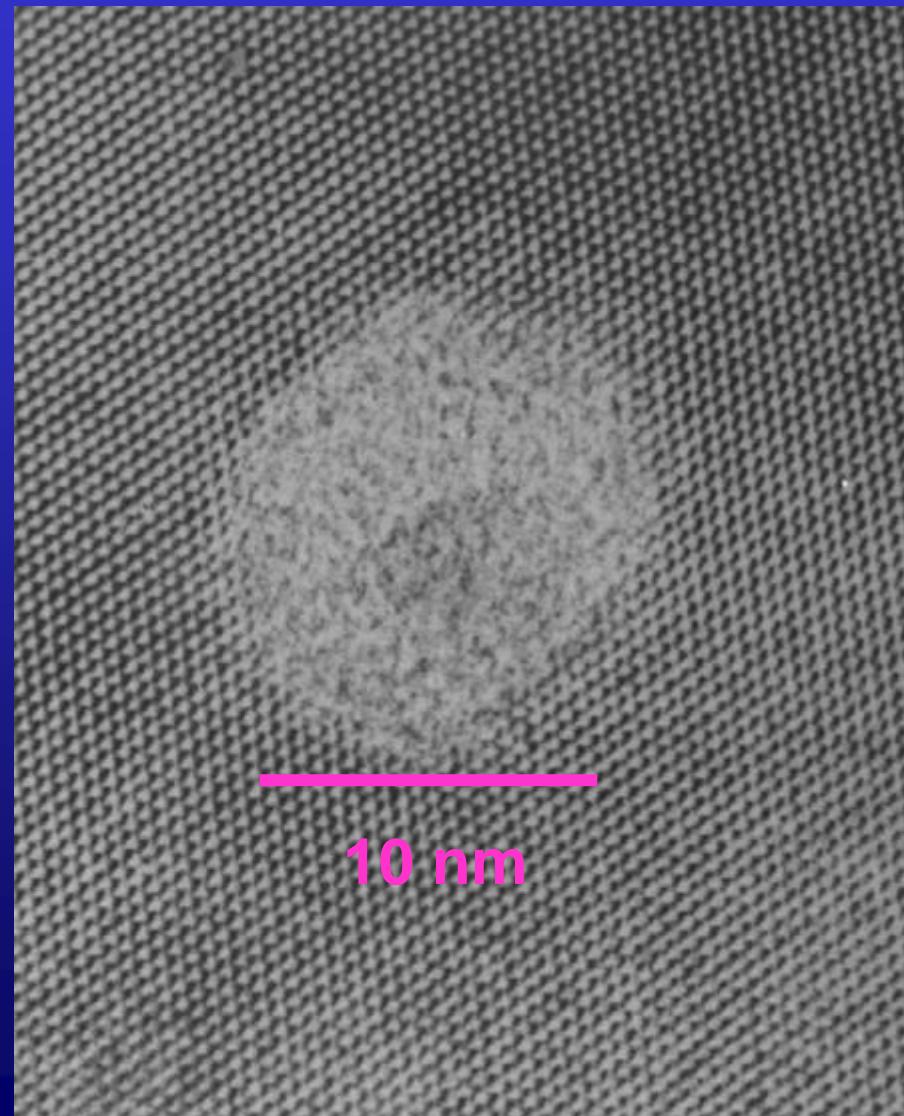


# Single ion tracks produced in amorphisable insulators @ ~ 10 MeV/u heavy ions

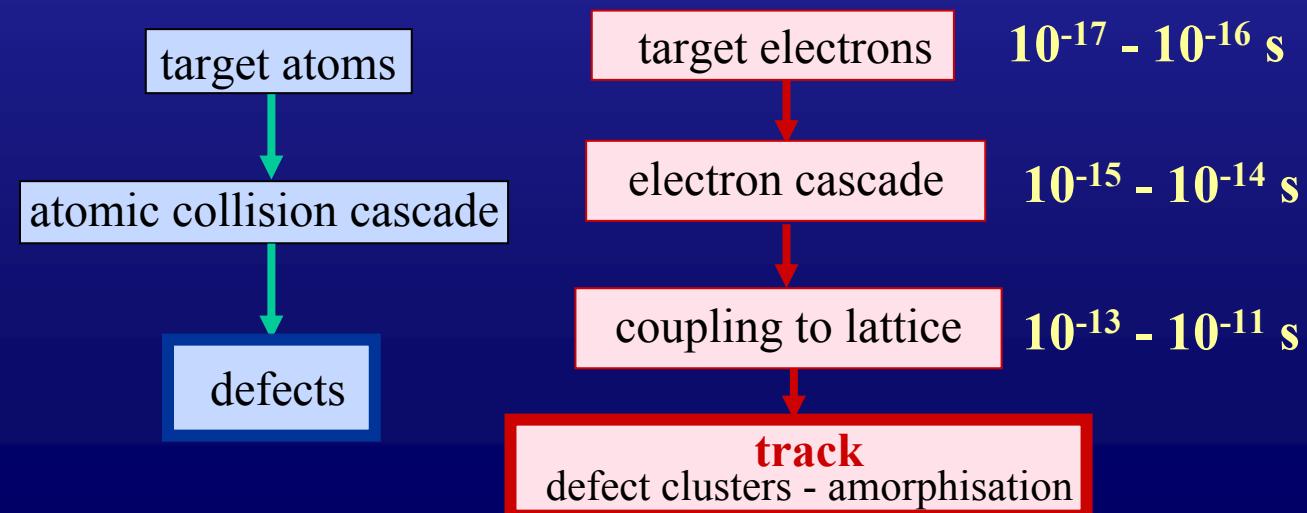
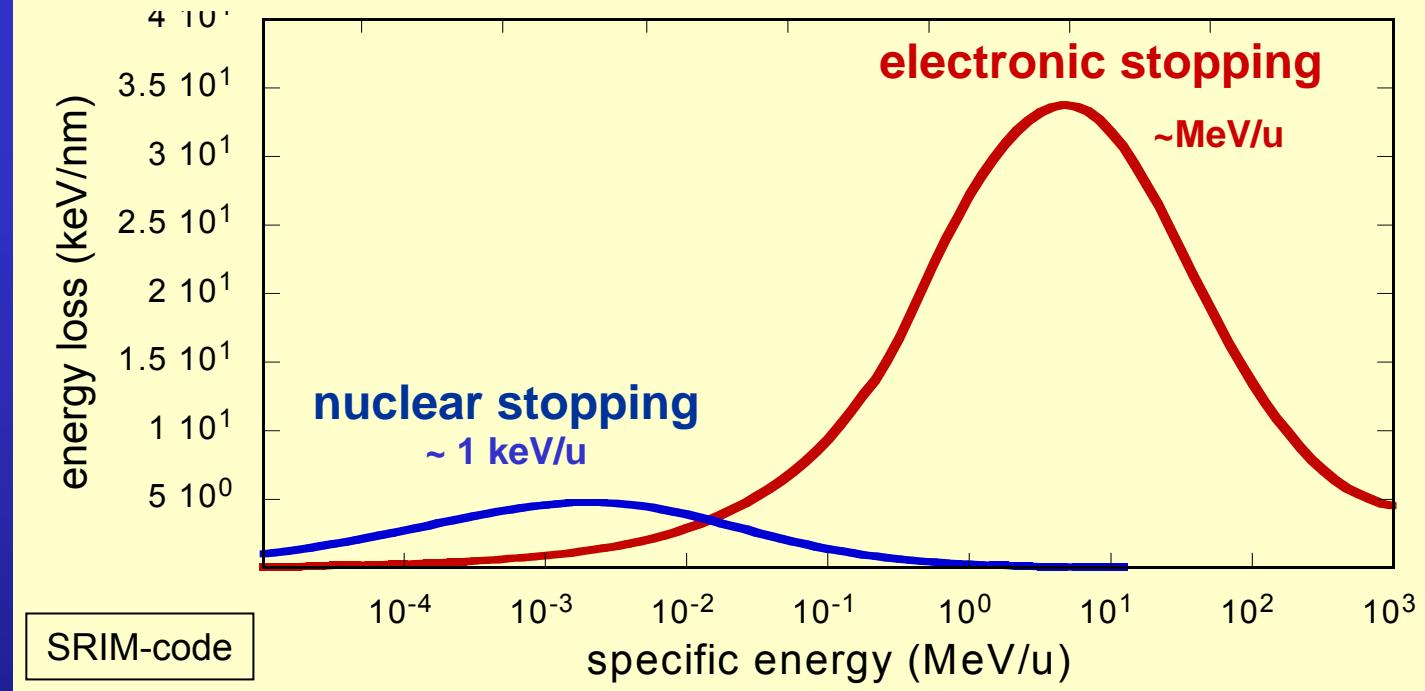
Au-ion trajectory in high T<sub>c</sub> superconductor



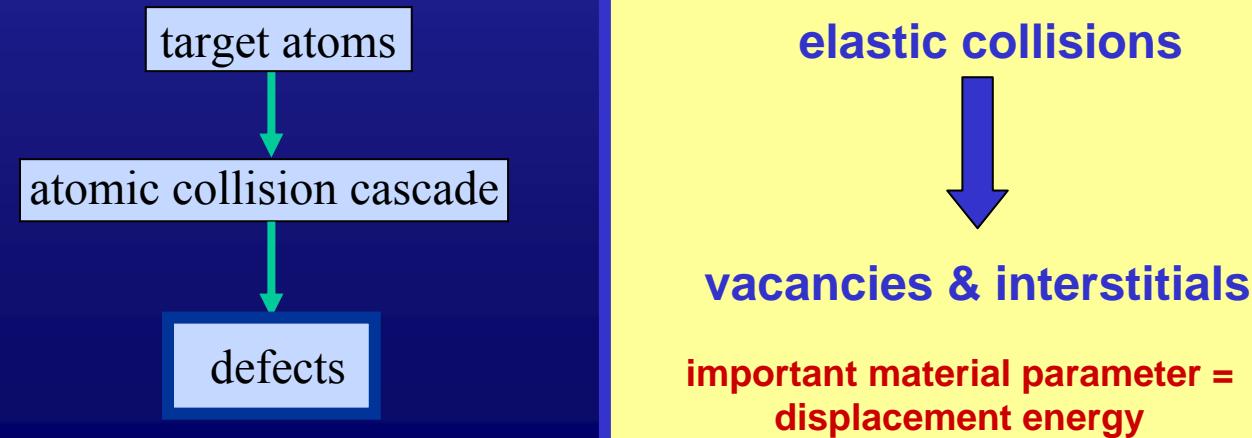
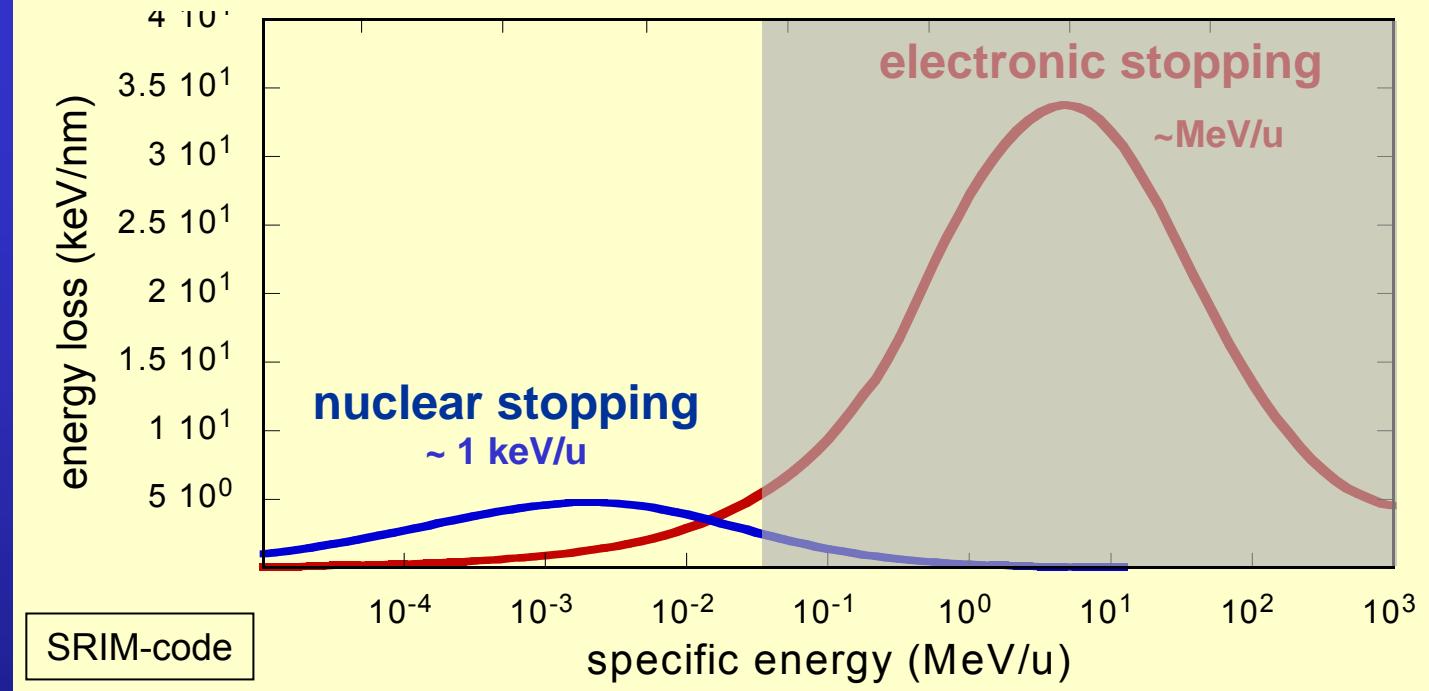
cross section of Pb-ion track in mica



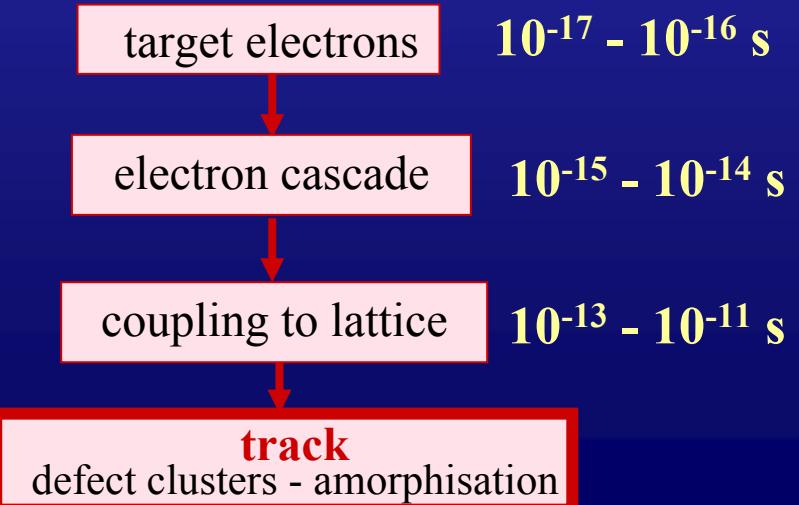
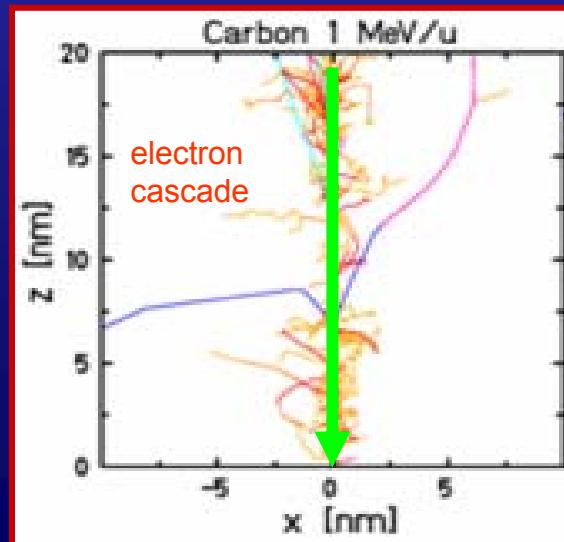
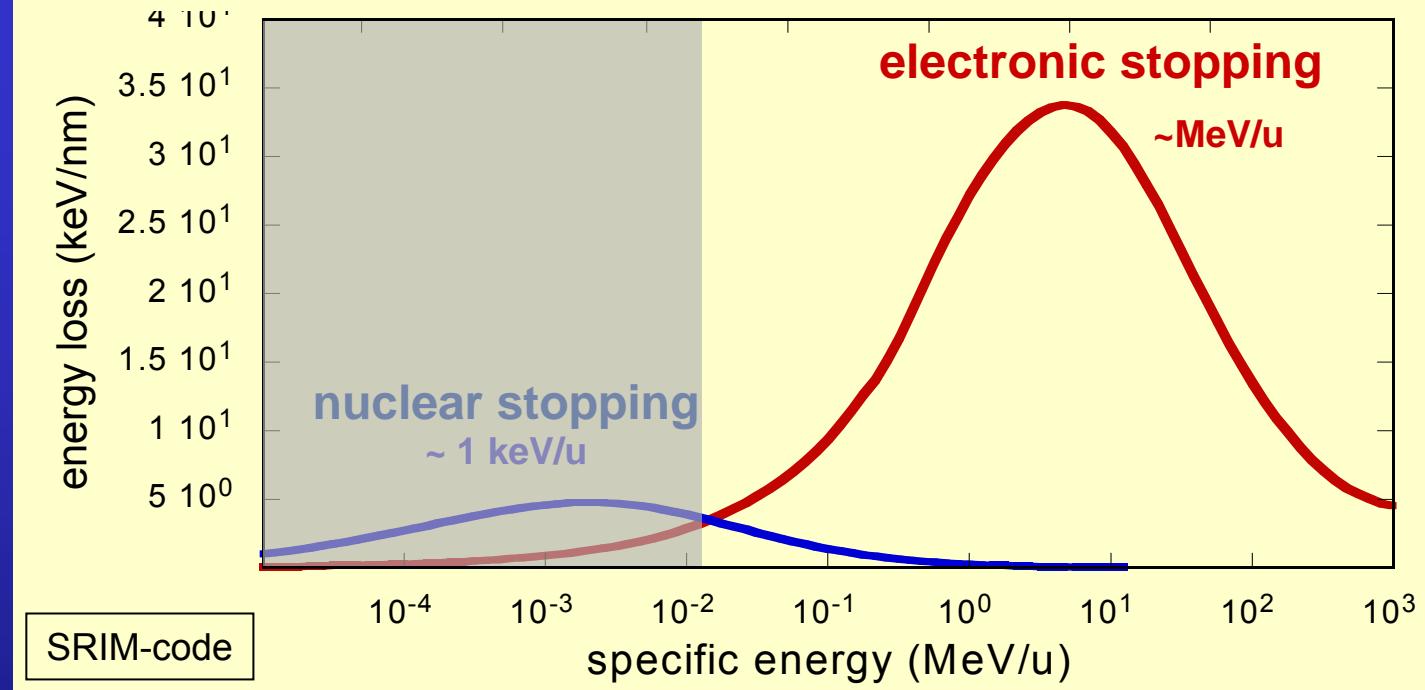
# energy deposition



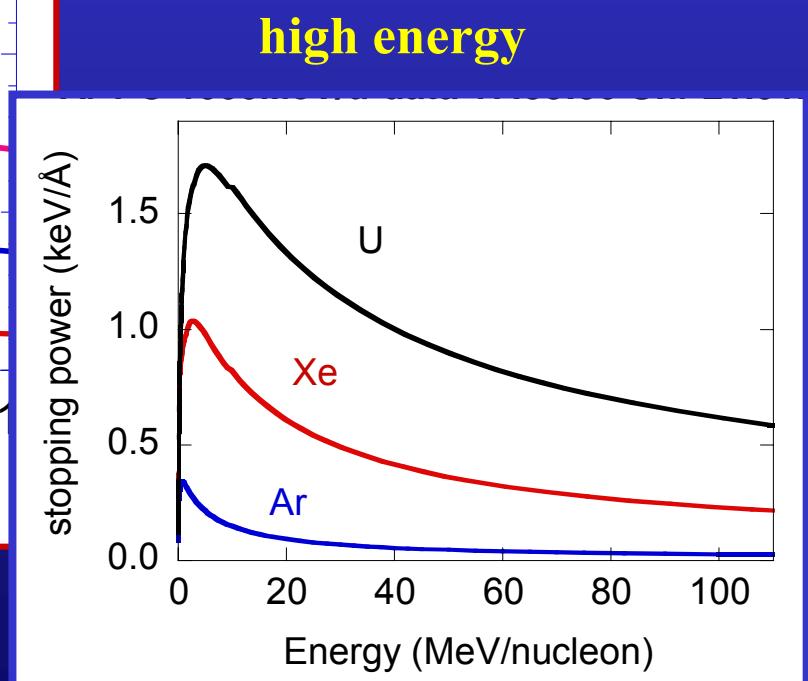
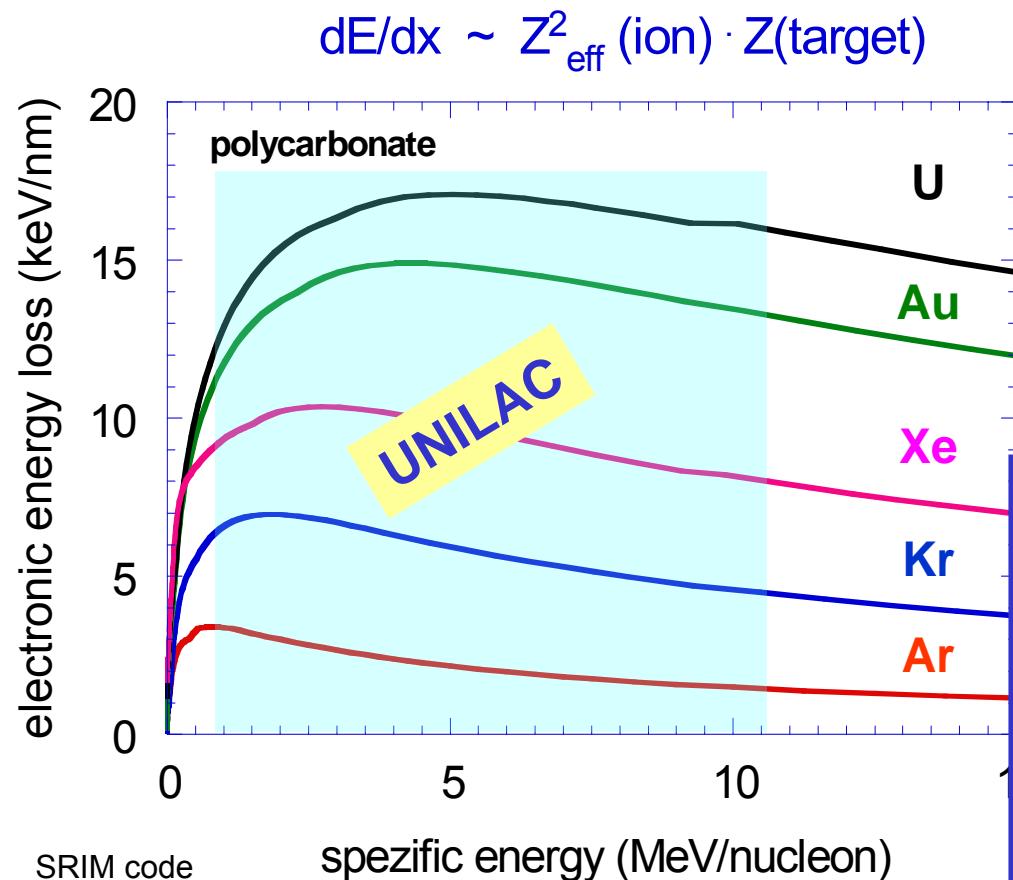
# energy deposition



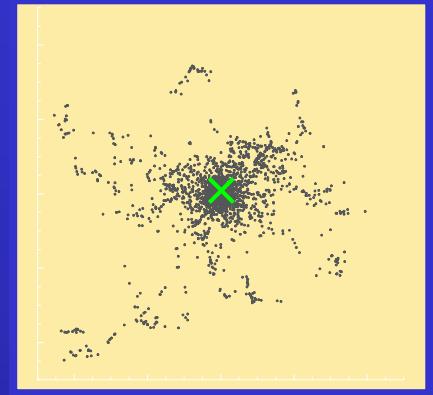
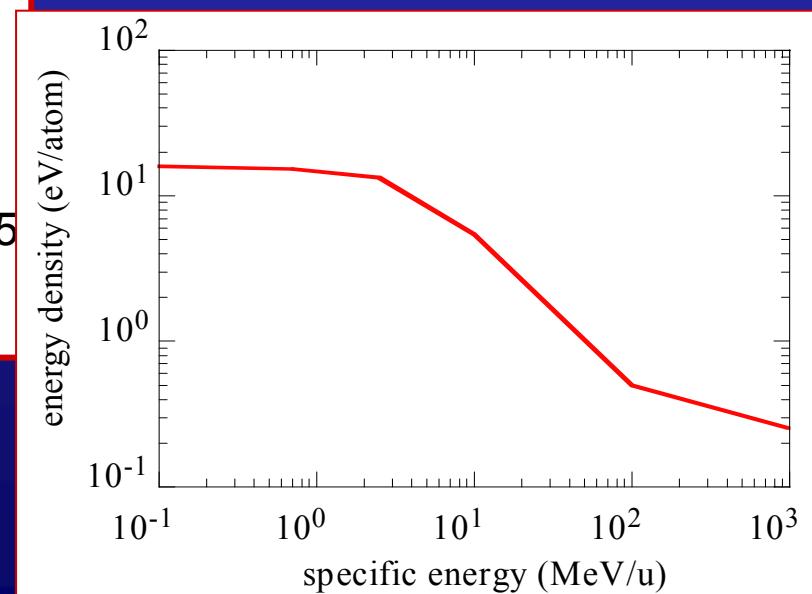
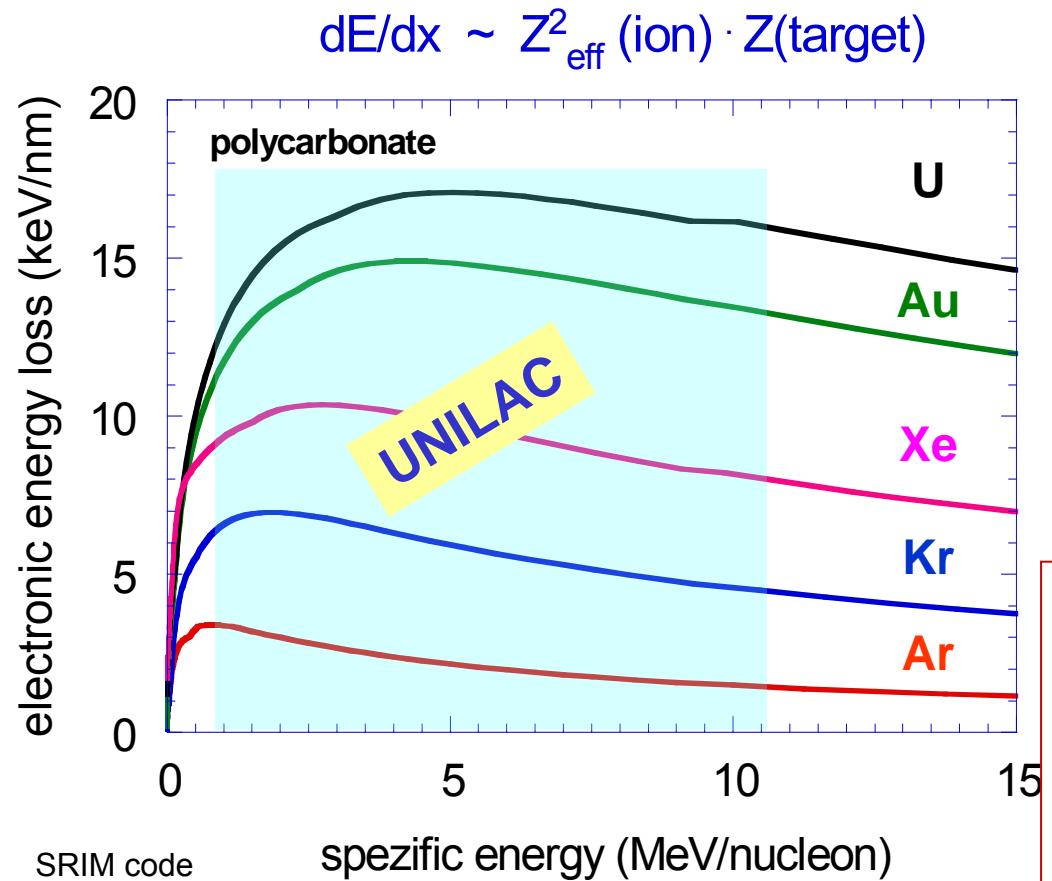
# energy deposition



# linear energy loss of different ions



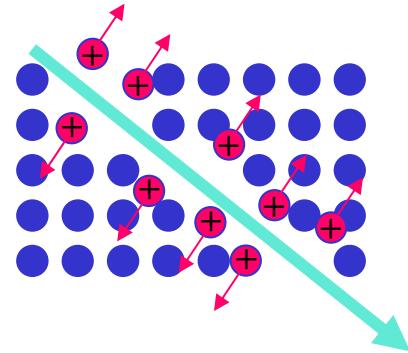
# linear energy loss of different ions



# Track formation models

## macroscopic

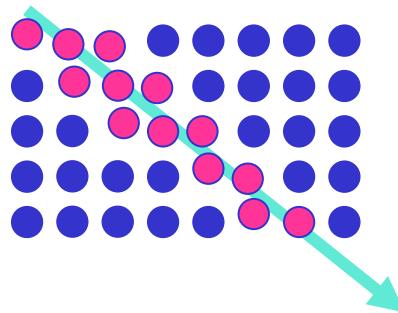
- ☐ **Coulomb explosion:** screening time by electrons  
few quantitative calculations



[Fleischer et al., J. Appl. Phys. 36 (1965) 3645]  
[Lesueur et al., Rad. Eff. Def. Sol. 126 (1993) 135]

- ☐ **thermal spike:** local melting and quenching  
transient thermodynamics?

[Desauer, Z. Physik 38 (1923) 12]  
[Seitz and Köhler Sol. St. Phys. 2 (1956) 305]  
[Lifshitz et al. J. Nucl. Ener. A12 (1960) 69]



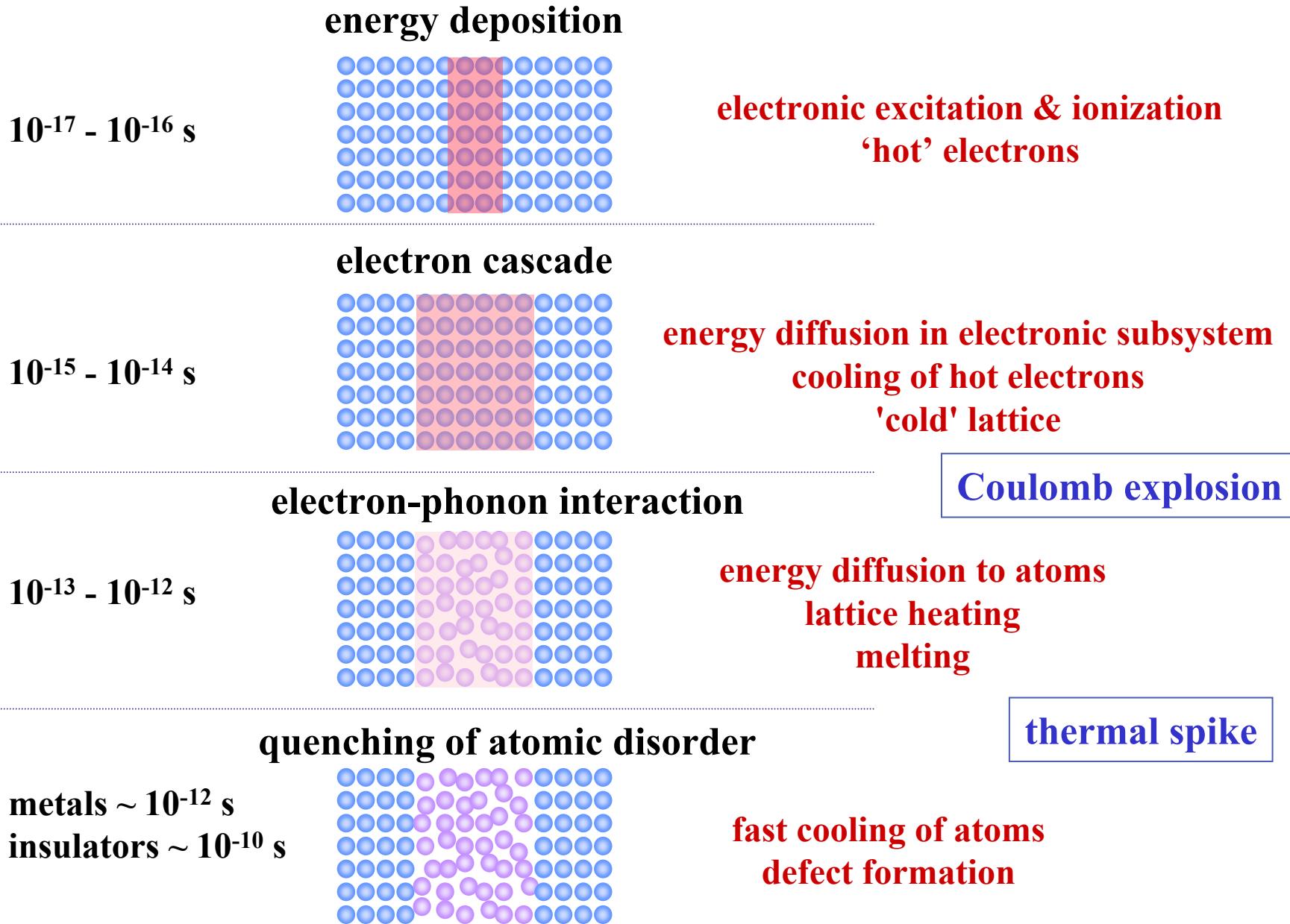
## microscopic

- ☐ **molecular dynamic calculations:** ab initio lattice calculations

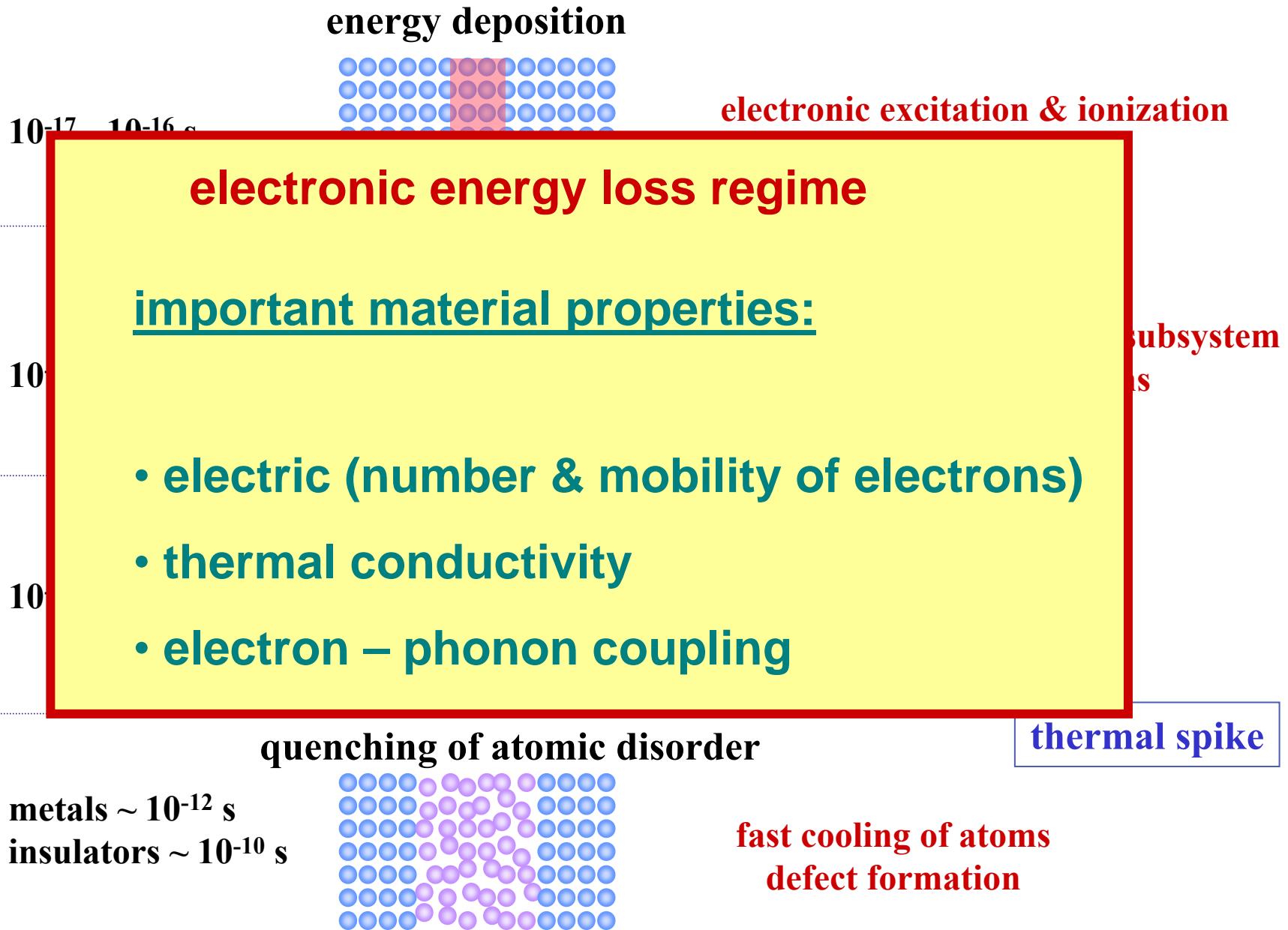
- electron subsystem not included
- interatomic potential?
- large computing times!

[Beuve et al. PRB 68 (2003) 125423 ]  
[Bringa NIMB 203 (2003) 1]

# Scheme of two-step process for track formation



# Scheme of two-step process for track formation



# Inelastic Thermal Spike Model

two-temperature model

Electrons     $C_e(T_e) \frac{\partial T_e}{\partial t} = \frac{1}{r} \frac{\partial}{\partial r} \left[ r K_e(T_e) \frac{\partial T_e}{\partial r} \right] - \underline{g}(T_e - T_a) + \underline{A(r,t)}$

Atoms        $C_a(T_a) \frac{\partial T_a}{\partial t} = \frac{1}{r} \frac{\partial}{\partial r} \left[ r K_a(T_a) \frac{\partial T_a}{\partial r} \right] + \underline{g}(T_e - T_a)$

~ ion energy loss

C = specific heat capacity  
K = thermal conductivity

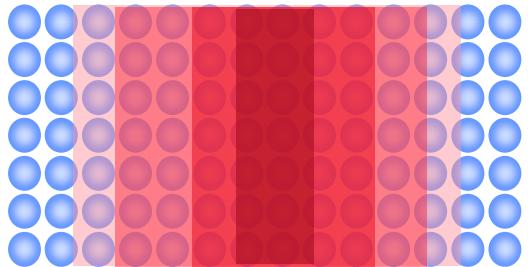
**electron-phonon coupling**

metals: Wang et al., J. Phys. : Condens. Matter 6 (1994) 6733  
Dufour et al. Bull. Mater. Sci. 22 (1999) 671

insulators: Toulemonde et al., Nucl. Instr. Meth. B166-167 (2000) 903

# Diffusion & Transfer of Energy - Thermal Spike

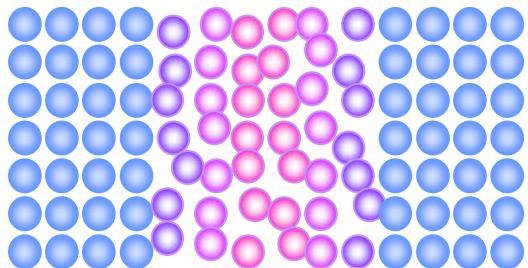
electronic subsystem



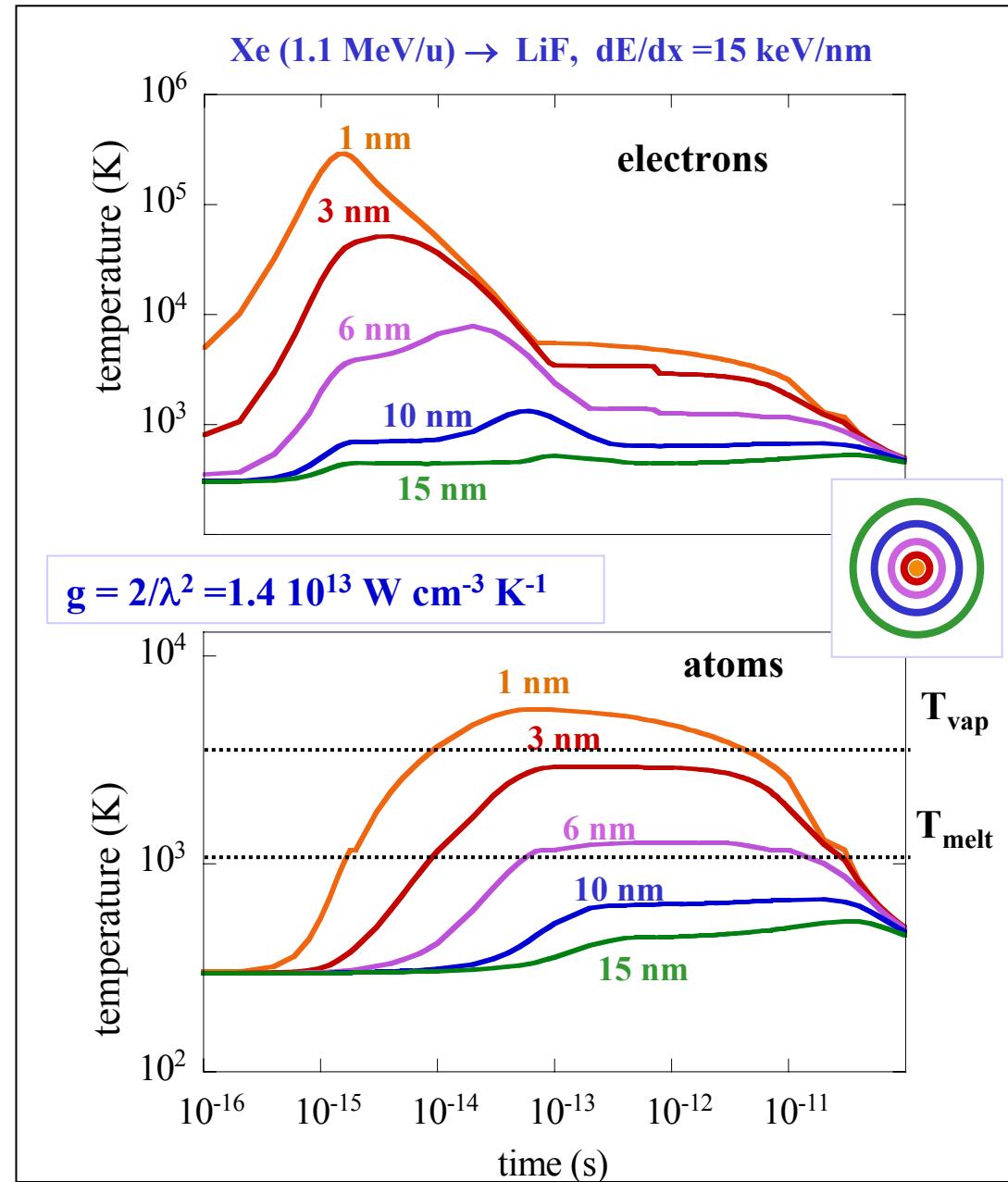
$$C_e(T_e) \frac{\partial T_e}{\partial r} = \frac{1}{r} \frac{\partial}{\partial r} \left( r K_e(T_e) \frac{\partial T_e}{\partial r} \right) - g \cdot (T_e - T) + A(r, t)$$

electron-phonon interaction

$$C(T) \frac{\partial T}{\partial r} = \frac{1}{r} \frac{\partial}{\partial r} \left( r K(T) \frac{\partial T}{\partial r} \right) + g \cdot (T_e - T)$$

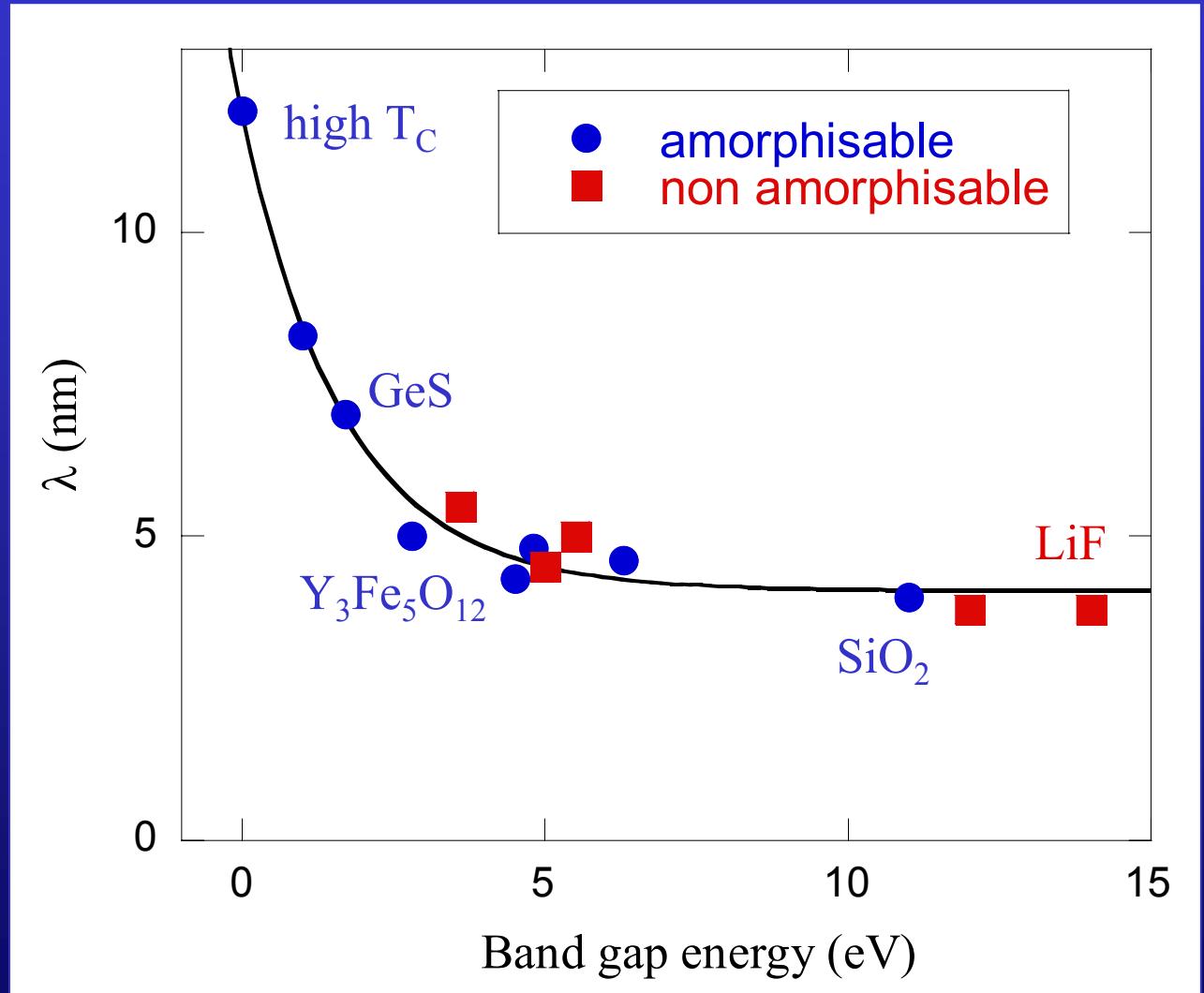


atomic subsystem



# Electron-phonon coupling: $\lambda$

High T<sub>c</sub>  
 BaFe<sub>12</sub>O<sub>19</sub>  
 GeS  
 Y<sub>3</sub>Fe<sub>5</sub>O<sub>12</sub>  
 SnO<sub>2</sub>  
 LiNbO<sub>3</sub>  
 Gd<sub>3</sub>Ga<sub>5</sub>O<sub>12</sub>  
 UO<sub>2</sub>  
 Y<sub>2</sub>O<sub>3</sub>  
 Y<sub>3</sub>Al<sub>5</sub>O<sub>12</sub>  
 SiO<sub>2</sub>  
 CaF<sub>2</sub>  
 LiF



# Track formation and defects in different materials

- metals
- semiconductors
- insulators

# Material sensitivity

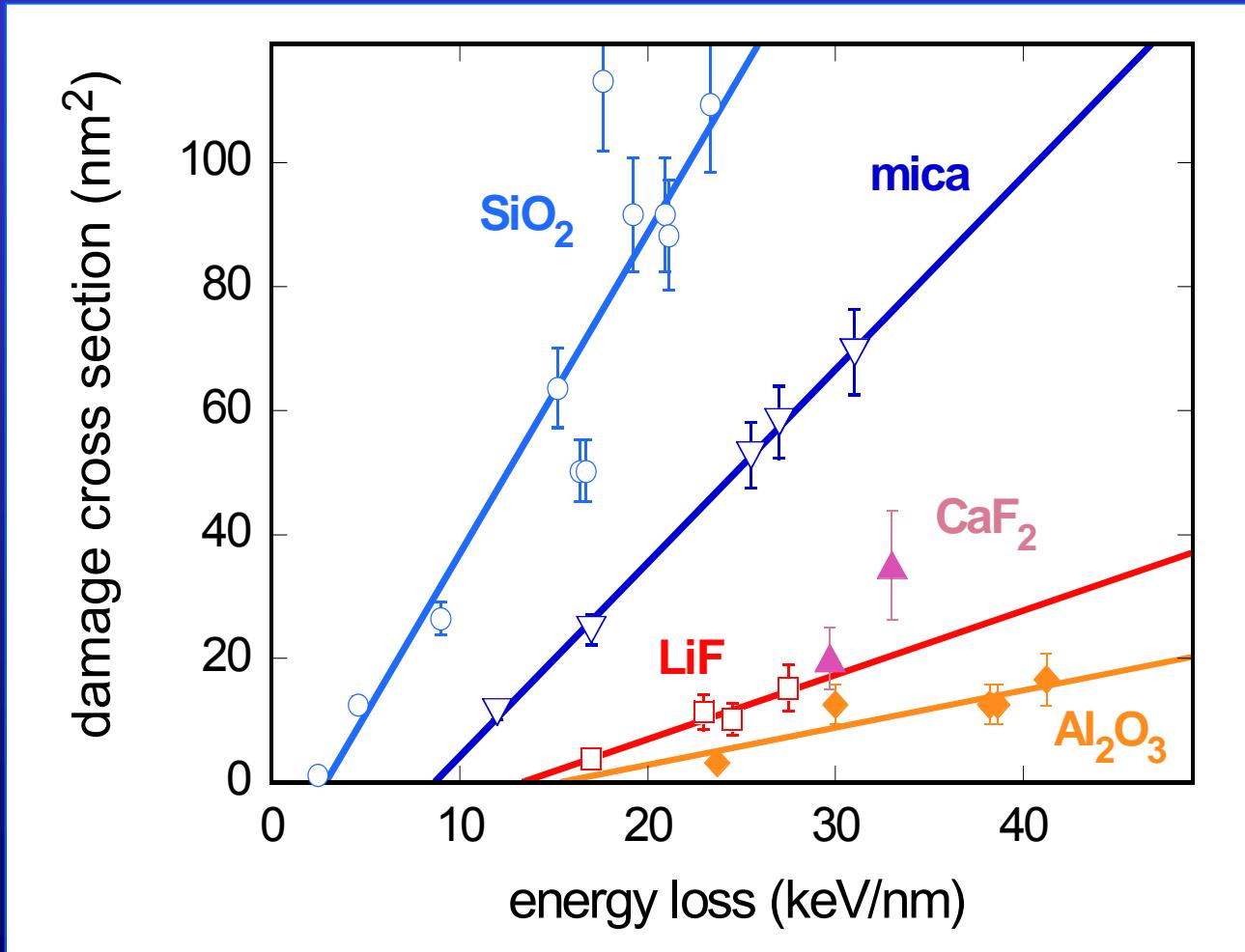
(phenomenological)

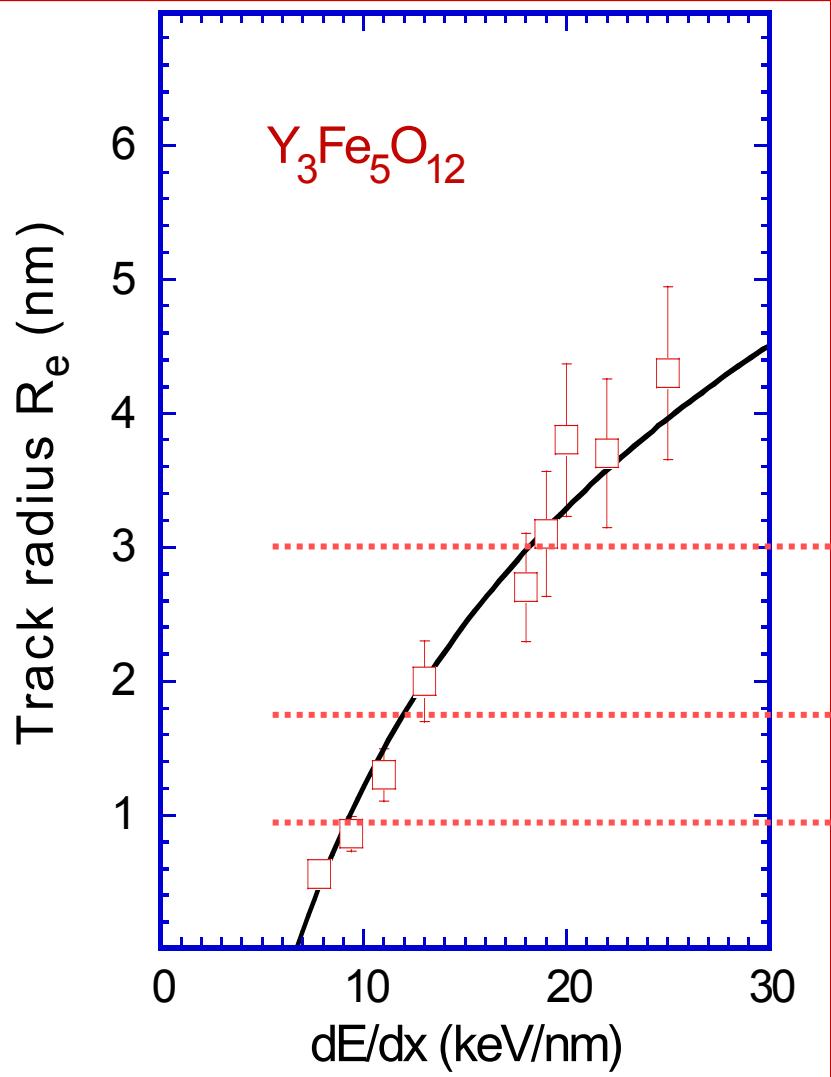
high sensitivity

low sensitivity

$dE/dx$ threshold	$\sim 1 \text{ keV/nm}$	$\sim 20 \text{ keV/nm}$	$\sim 50 \text{ keV/nm}$
<u>insulators</u>		<u>semi-conductors</u>	<u>metals</u>
😊 polymers	😊 amorphous Si	😊 amorphous alloys	
😊 oxides, spinels	😊 GeS, InP, $\text{Si}_{1-x}\text{Ge}_x$	😊 Fe, Bi, Ti, Co, Zr	
😊 ionic crystals	😢 Si, Ge	😢 Au, Cu, Ag...	
😢 diamond			

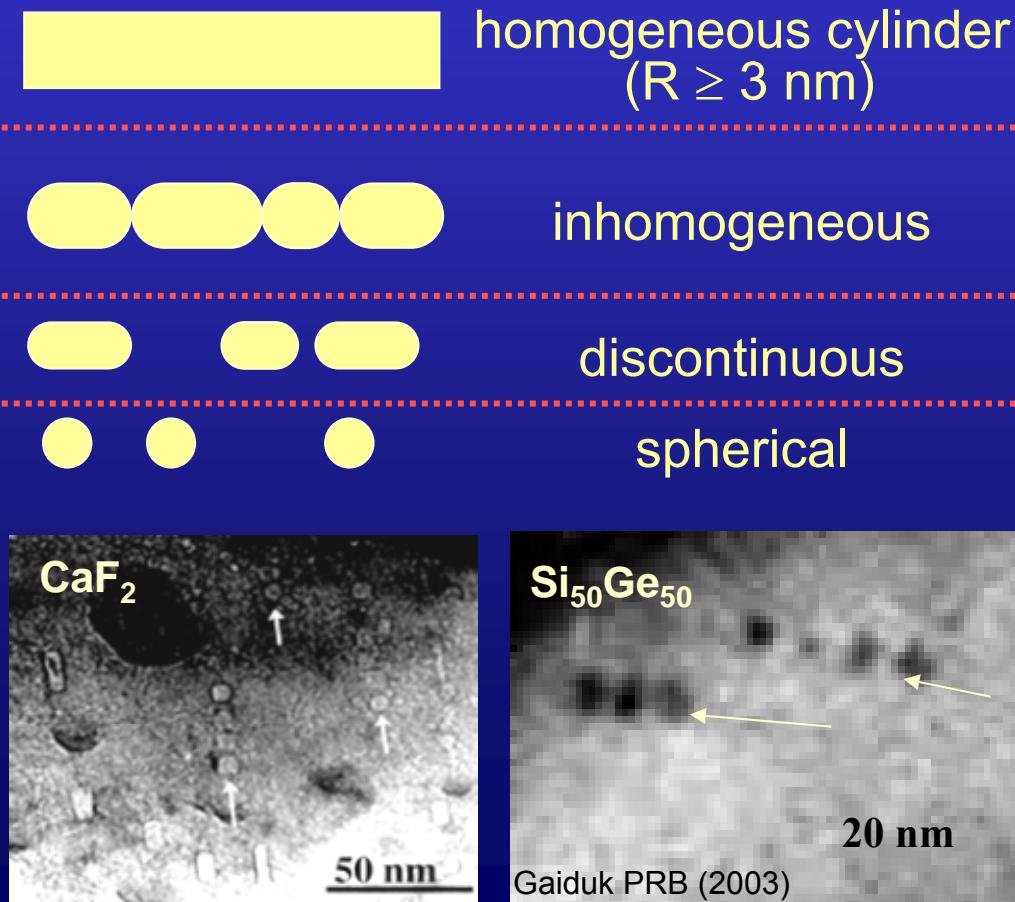
# track size and energy loss threshold



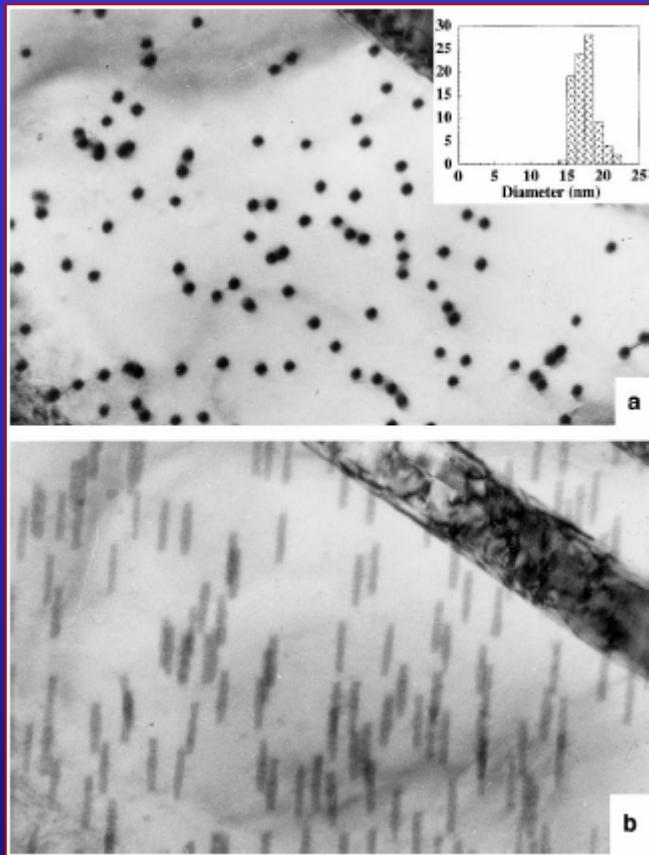


Toulemonde et al., Sol. State Phen. 30/31 (1993) 477

## Damage morphology



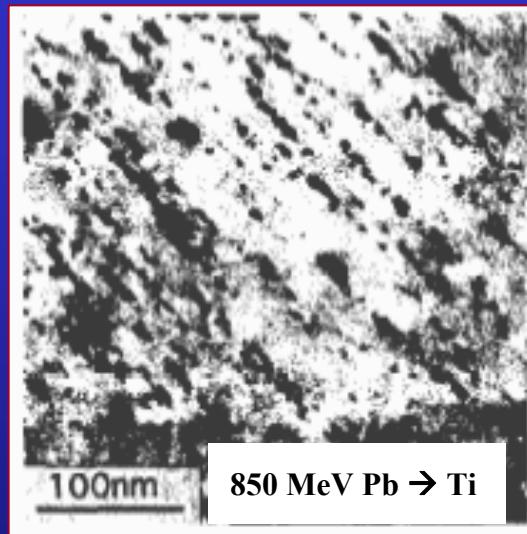
structural changes in  
intermetallic compound NiTi



Barbu et al., NIMB 145 (1998) 354

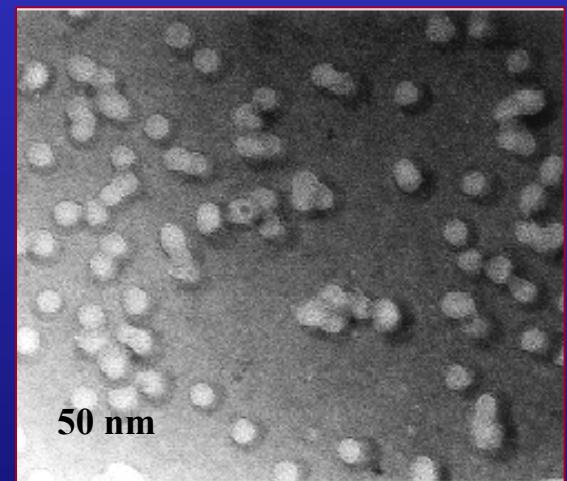
# Tracks in metals

discontinuous tracks in Ti



Dunlop et al. NIM B 112 (1996) 23

30 MeV C<sub>60</sub> → Ni<sub>3</sub>B  
amorphous tracks



Dunlop et al. NIM B 146 (1998) 222

## sensitive metals

pure metals: Fe, Ti, Co, Zr, Bi

metallic compounds: NiB, FeCrNi, TiNi, etc

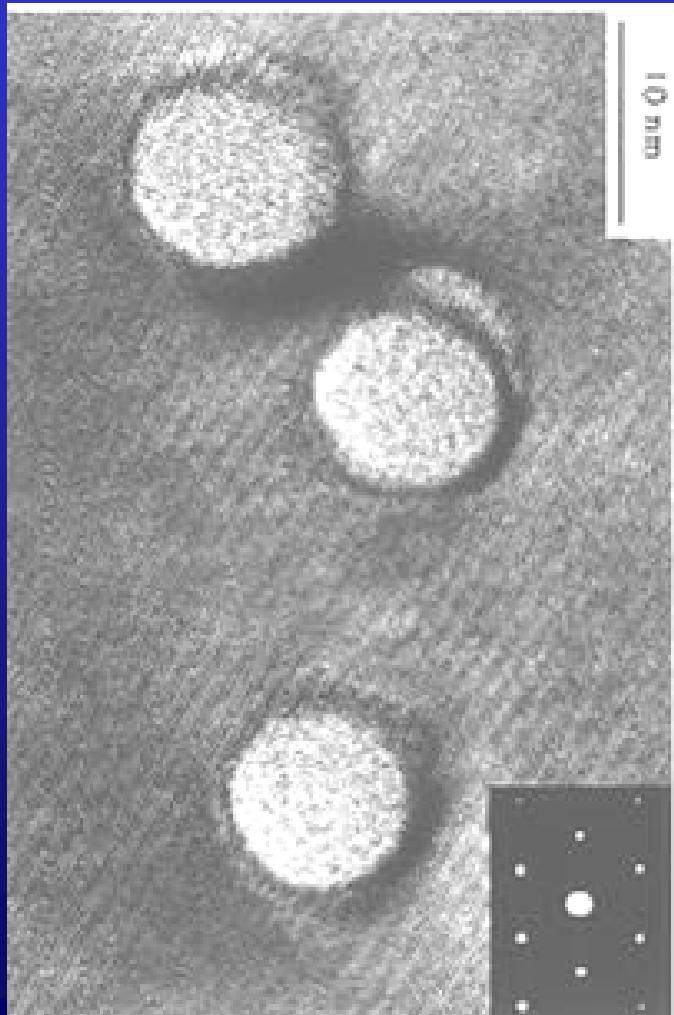
metallic glasses: PdSi, FeB, etc

## insensitive metals

Nb, Cu, Ni, Pt,  
W, Ag, Pd, Au

# Tracks in semiconductors

# no tracks in Si by monoatomic ions (up to U ions) but amorphous tracks by C<sub>60</sub> clusters



30 MeV C<sub>60</sub> clusters  $\Rightarrow$  (111) Si

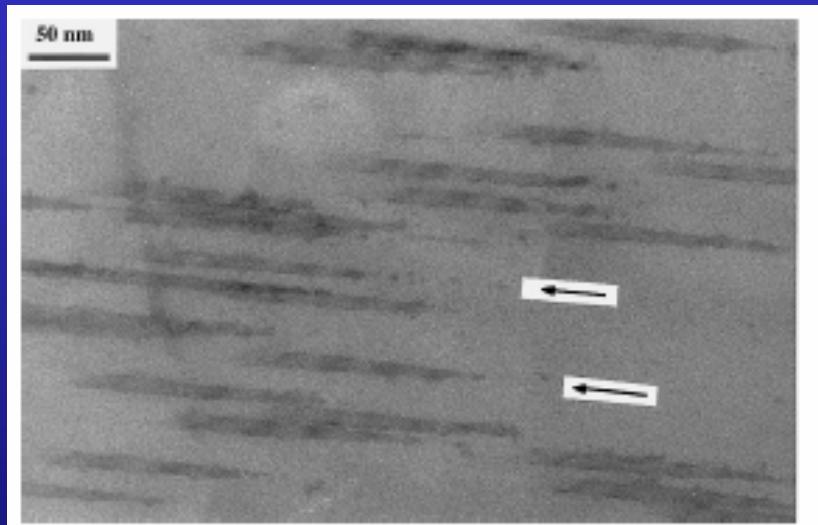
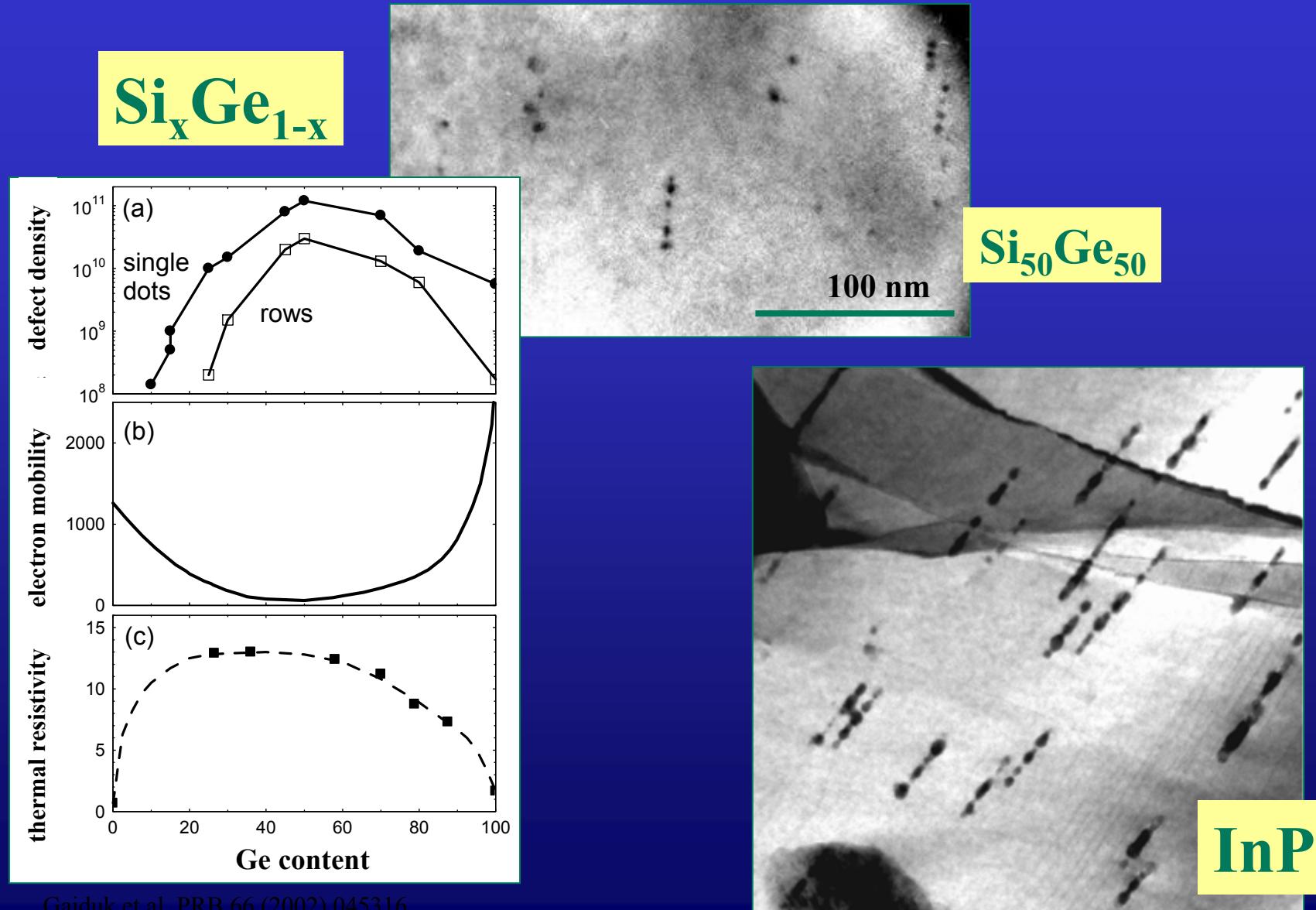


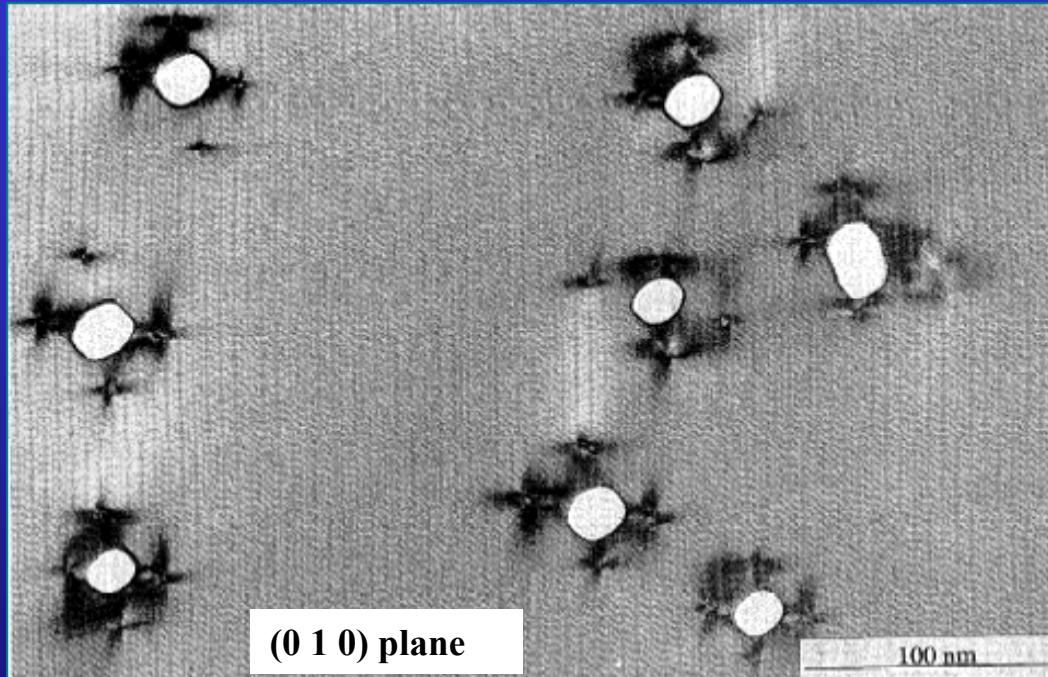
Fig. 3. Bright field electron micrograph of a monocrystalline silicon target irradiated at grazing incidence ( $\approx 80^\circ$  of normal incidence) with 30 MeV C<sub>60</sub> cluster ions. The micrograph is taken without any reflection strongly excited.

Dunlop et al., NIMB 146 (1998) 302  
Canut et al., NIMB 146 (1998) 296

# discontinuous tracks in semiconducting compounds

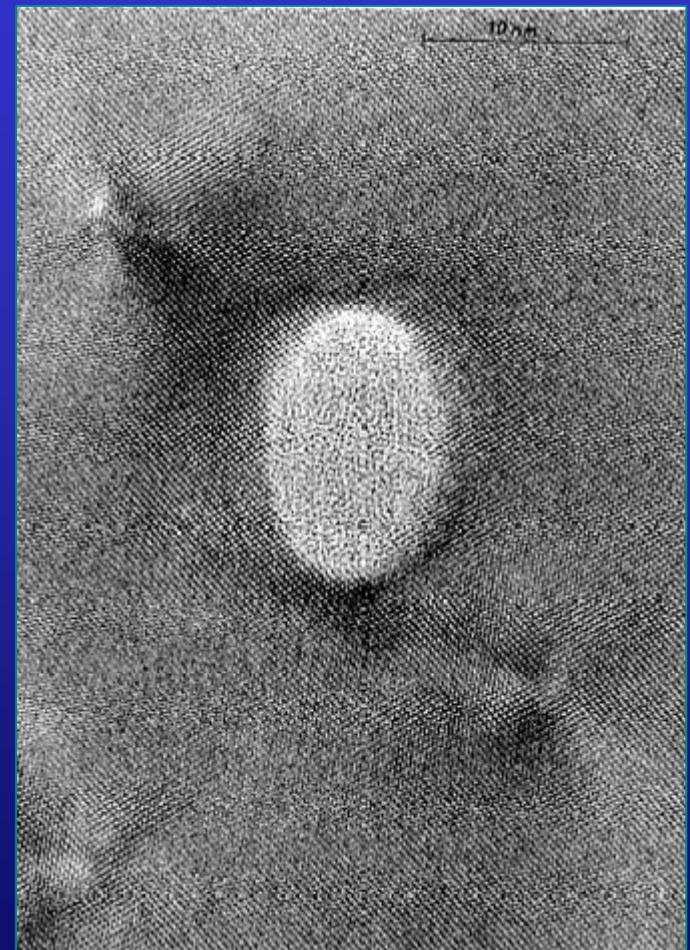


# amorphous tracks in narrow bandgap GeS



layered structure,  $E_g = 1.65$  eV

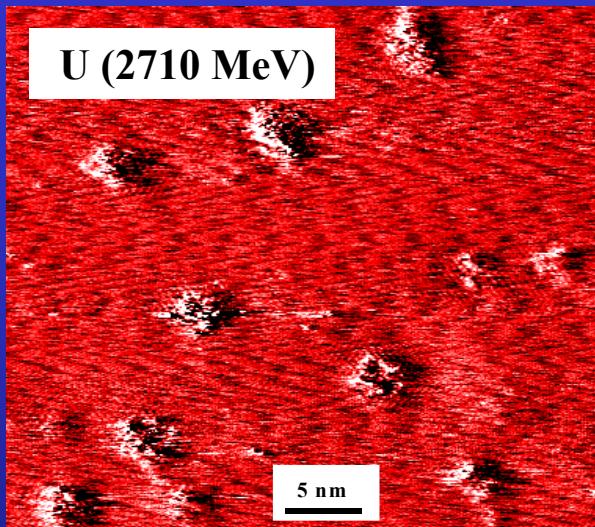
lattice constants:  $a = 0.429$  nm  
 $c = 0.365$  nm



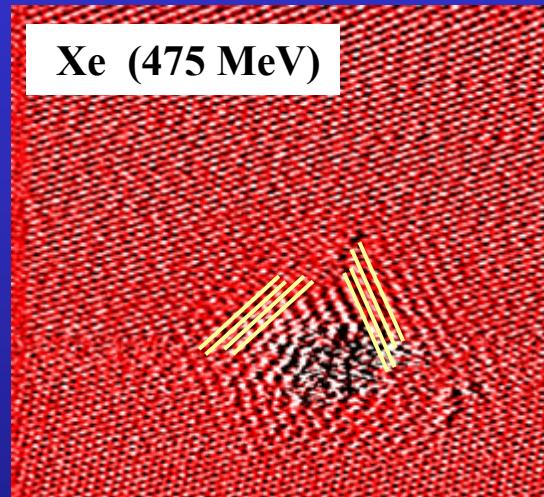
2.7 GeV U → GeS

# Tracks in carbon-based materials

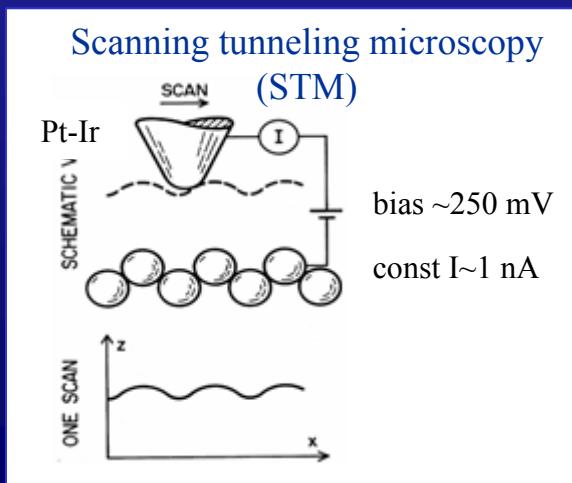
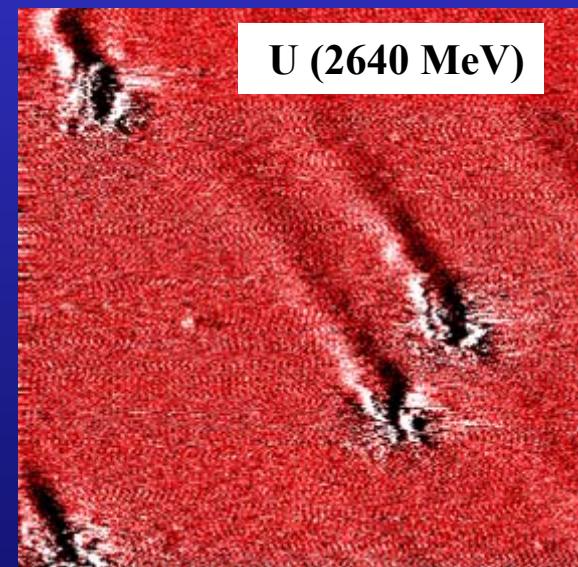
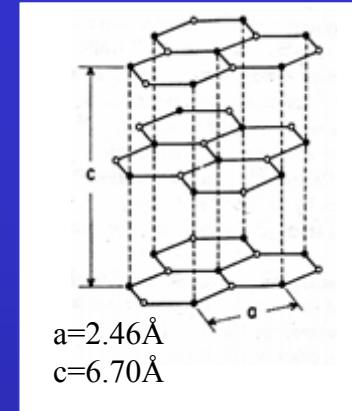
# Graphite (highly oriented pyrolytic, HOPG)



30 nm x 30 nm

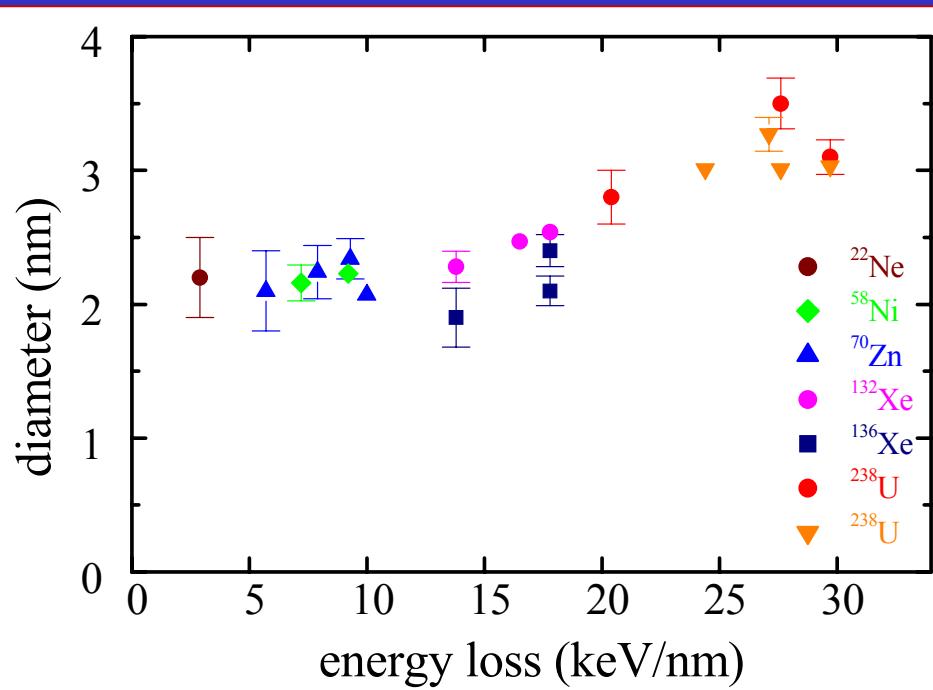


15 nm x 15 nm

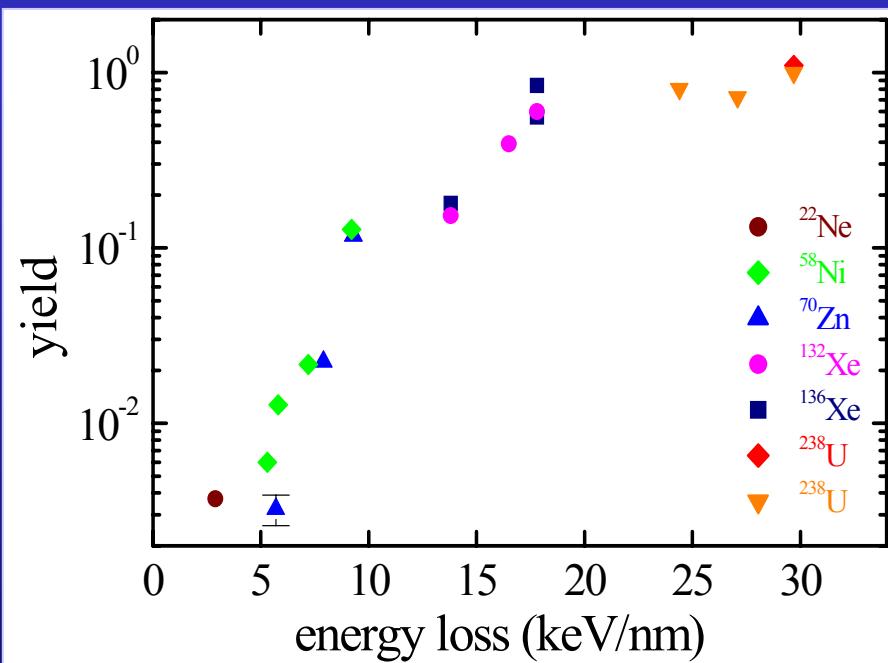


Liu et al, PRB 64 (2001) 184115  
NIMB 212 (2003) 303

# track diameter in HOPG



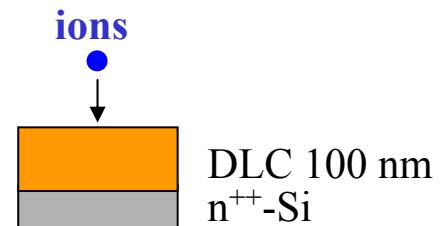
# track formation efficiency



- extremely small track diameters
- 100% track efficiency only above ~18 keV/nm

# Ion tracks diameter in DLC

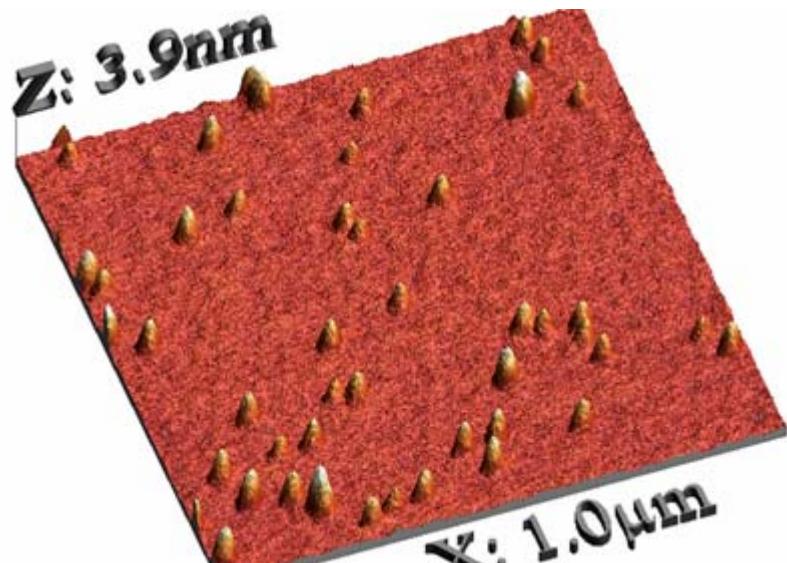
1 GeV U-ions ( $5 \times 10^9 \text{ cm}^{-2}$ ) → DLC



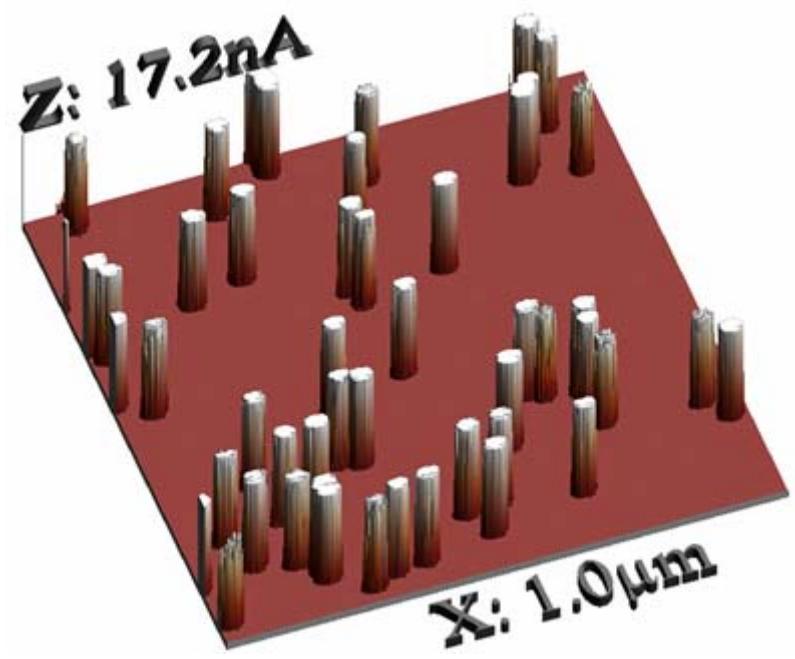
sp<sup>3</sup>-bonds: 70 - 80 %

## AFM measurements

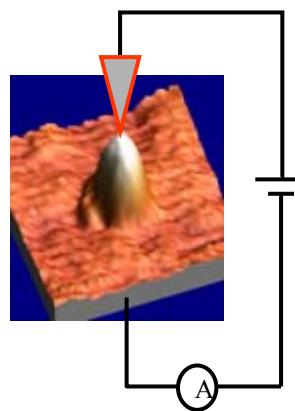
topography



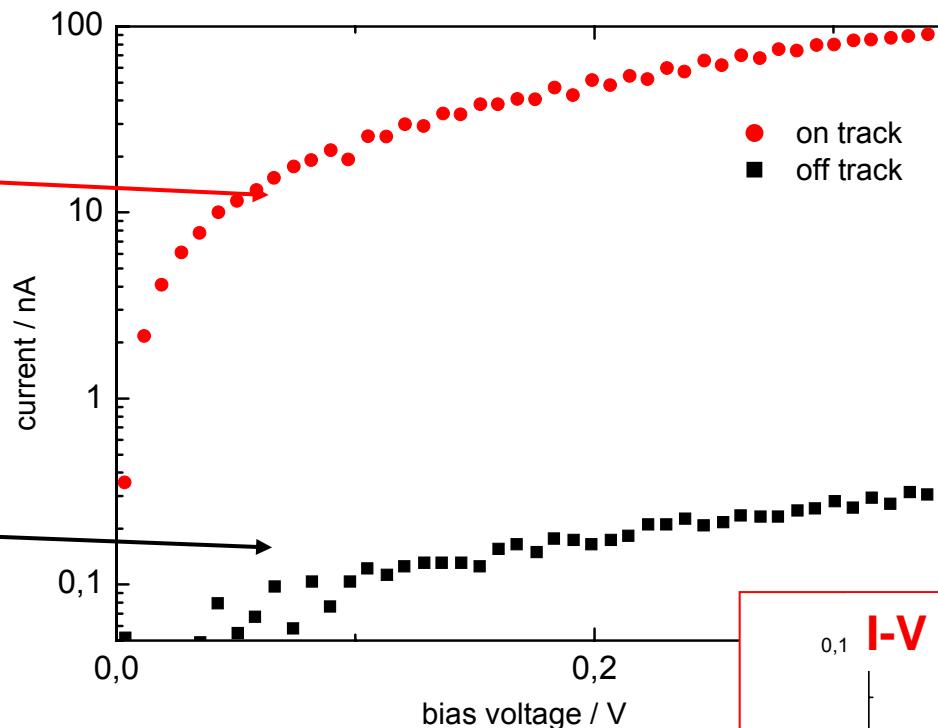
current mapping



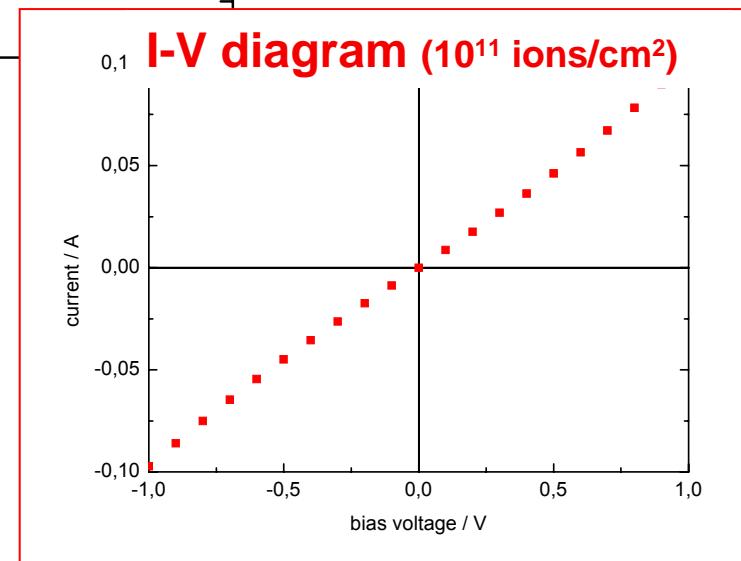
# I-V diagram of single track and off-track regions



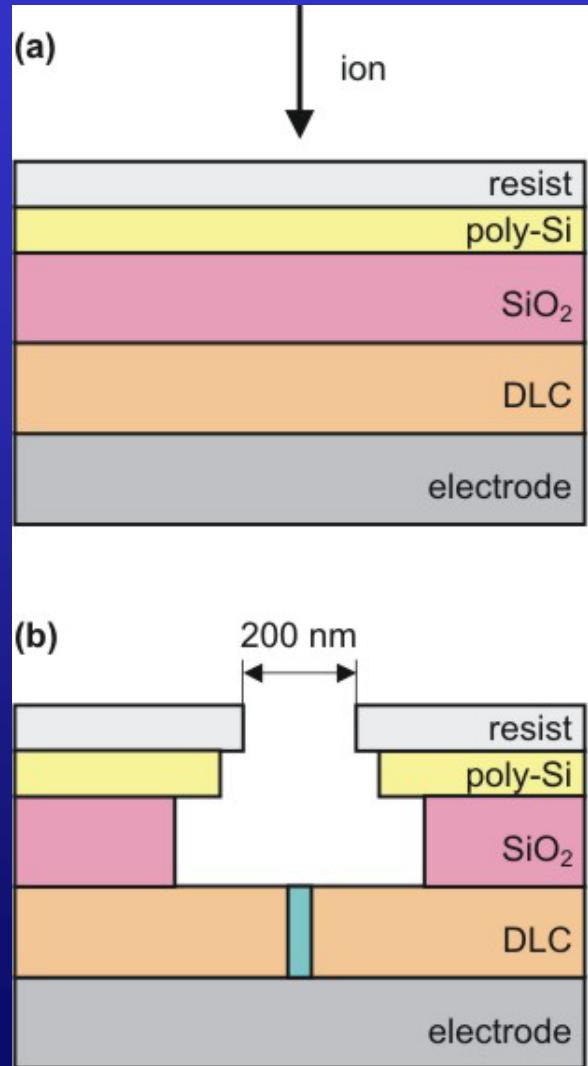
off track



( $U = 0.35$  V (AFM tip – substrate))  
max. current = 98 nA  
current density  $\sim 1 \times 10^5$  A/cm $^2$   
conductivity  $\sim 2.8$  S/cm.

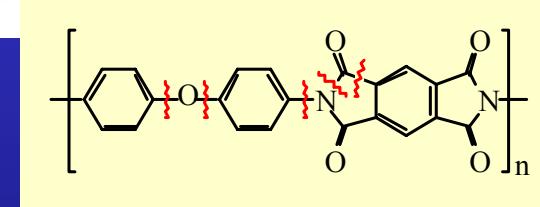


# possible field emitting device

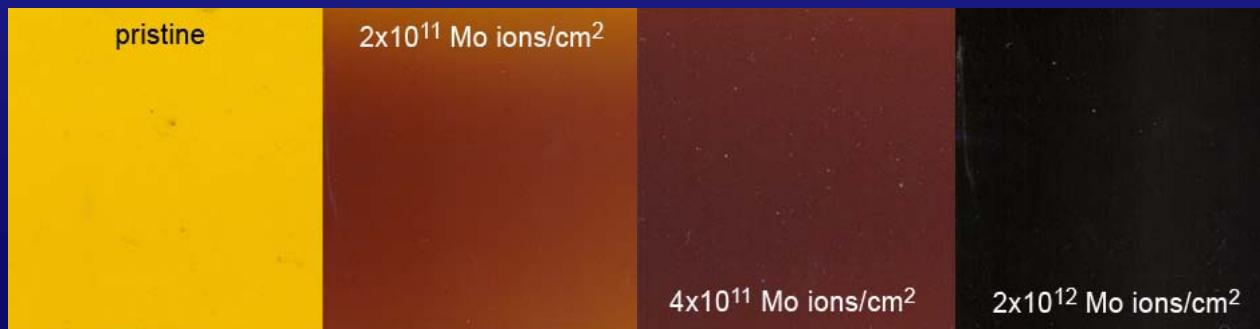


# Polymers

- chain scission
- cross linking
- formation of radicals
- amorphisation etc

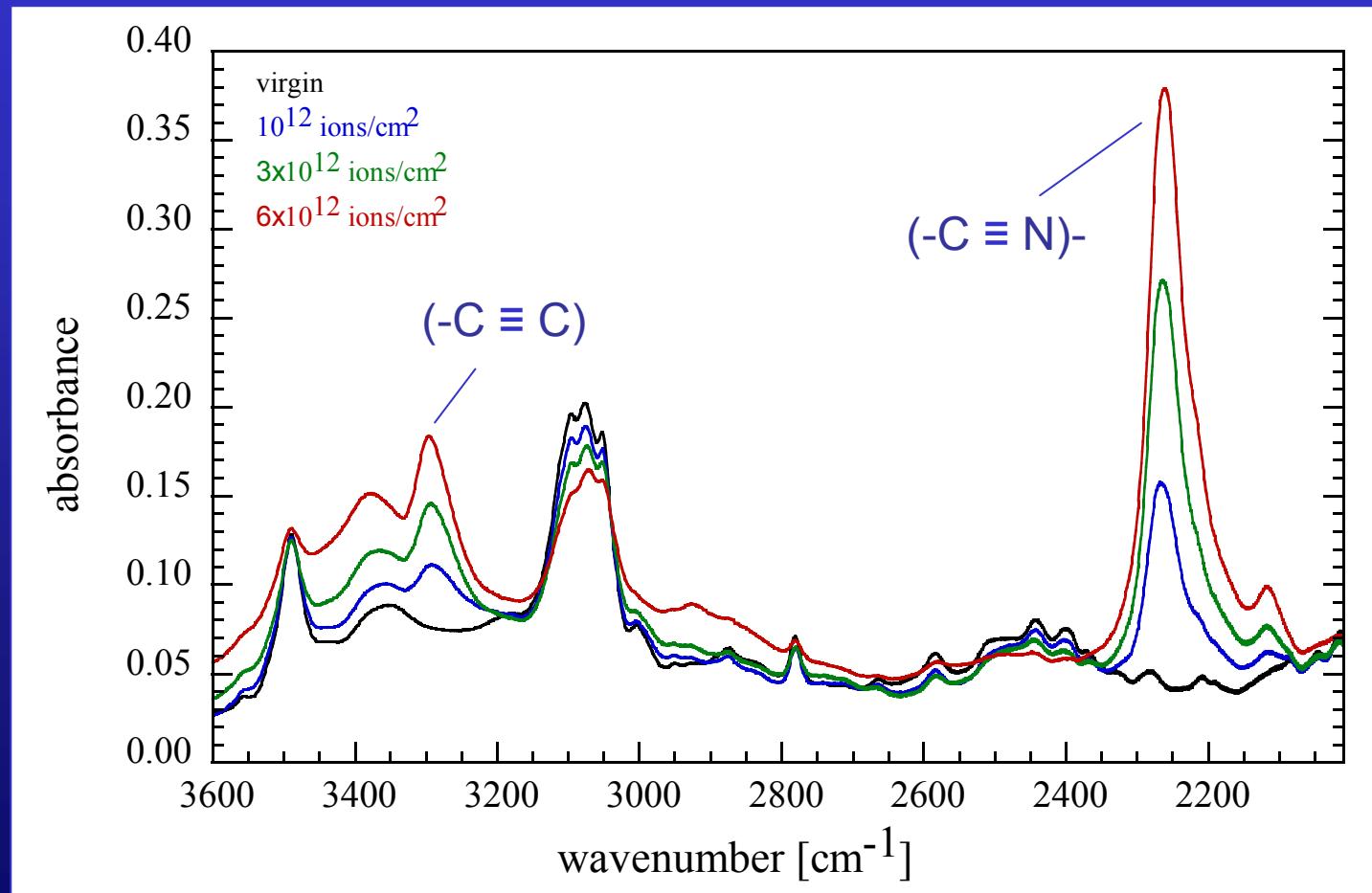


- outgassing of small molecules ( $\text{CO}_n$ ,  $\text{C}_n\text{H}_m$ ,...)
- creation of unsaturated bonds (e.g.  $-\text{C} \equiv \text{C}$ ,  $-\text{C}=\text{C}$ )
- graphitization



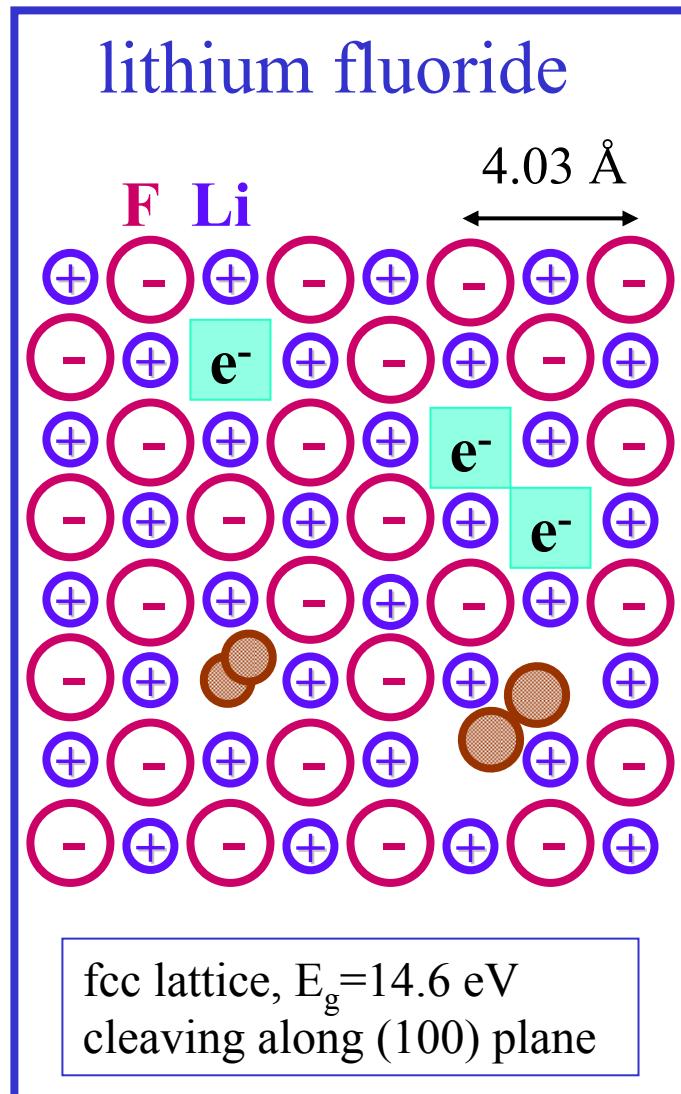
graphitization of Kapton increasing as a function of ion fluence

# Infrared spectroscopy: unsaturated bonds



# Defect creation in ionic crystals

LiF, NaCl, KCl, MgF<sub>2</sub>, CaF<sub>2</sub>, BaF<sub>2</sub>



non-amorphisable !!

color centers

F-center

F<sub>2</sub>-center

H-center

V<sub>K</sub>-center

electron centers

Frenkel pair

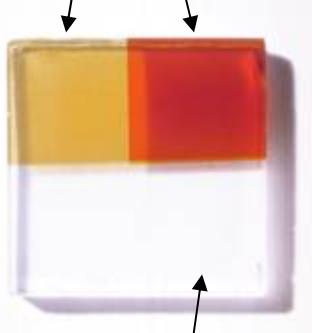
hole centers

# Spectroscopy of color centers

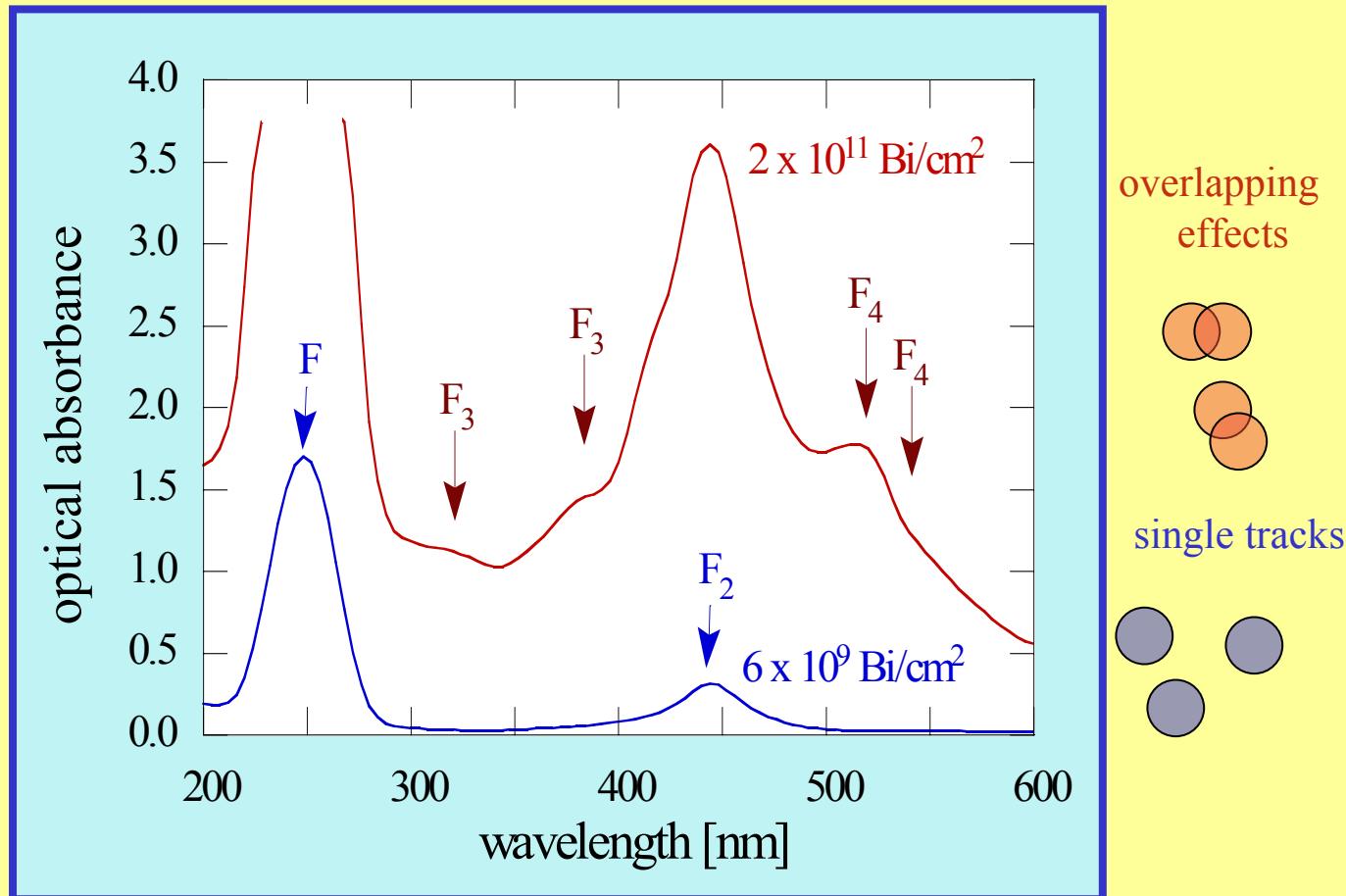
## LiF crystal

irradiated with Bi ions

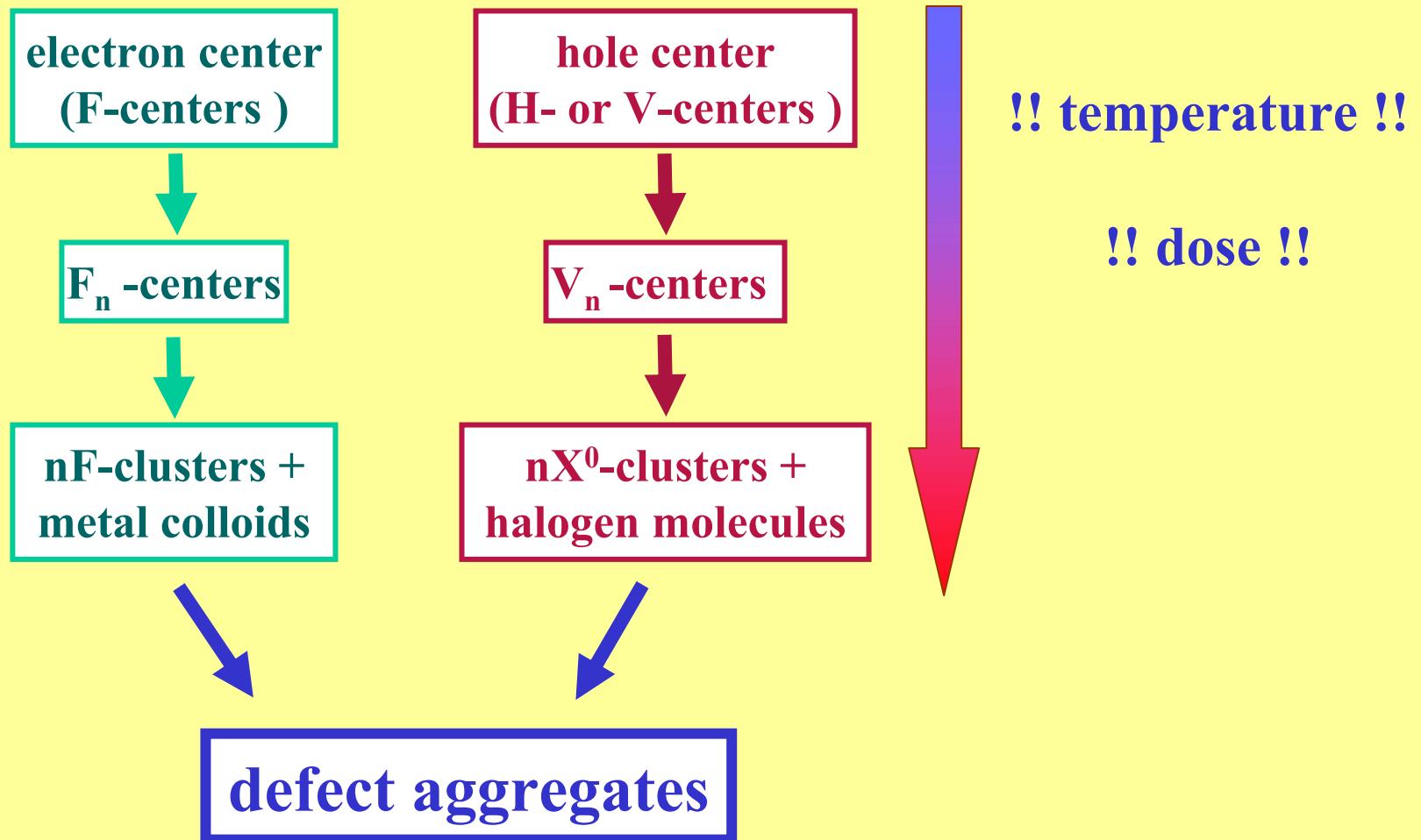
2      6 MeV/u



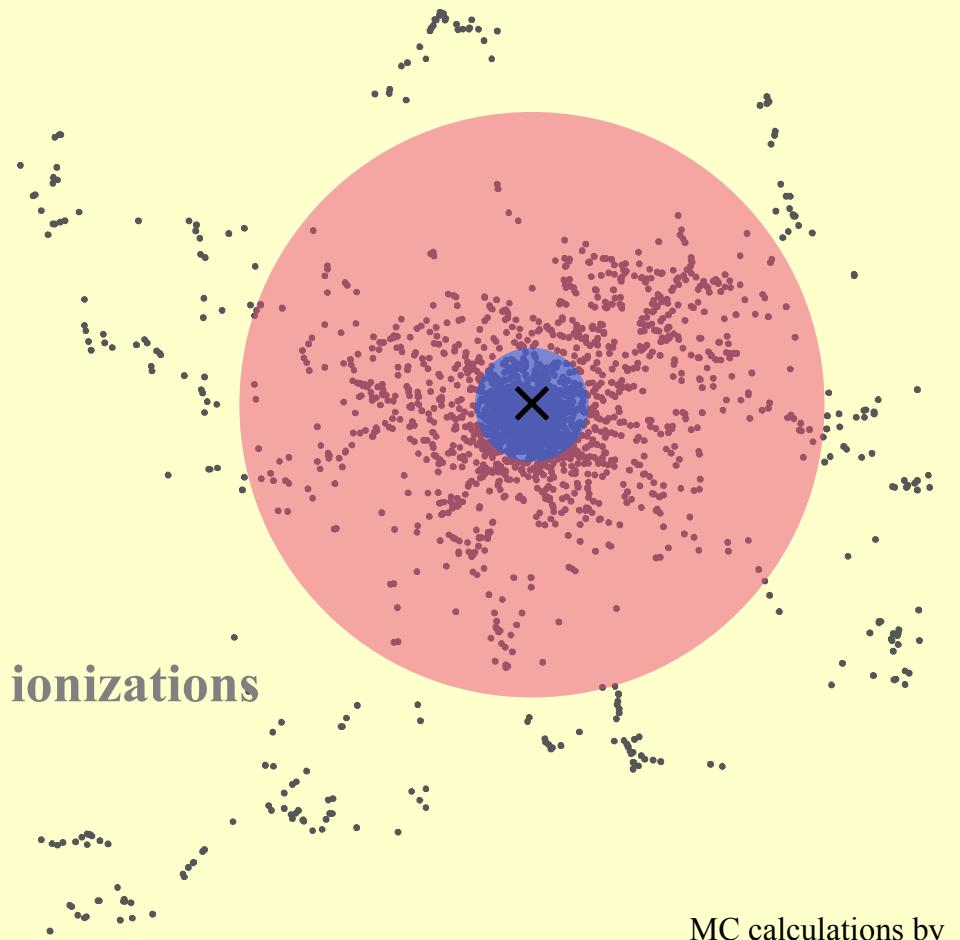
virgin



# Aggregation of single defects



# Scheme of track damage in LiF



**core (aggregates)**

**radius**      **1-2 nm**

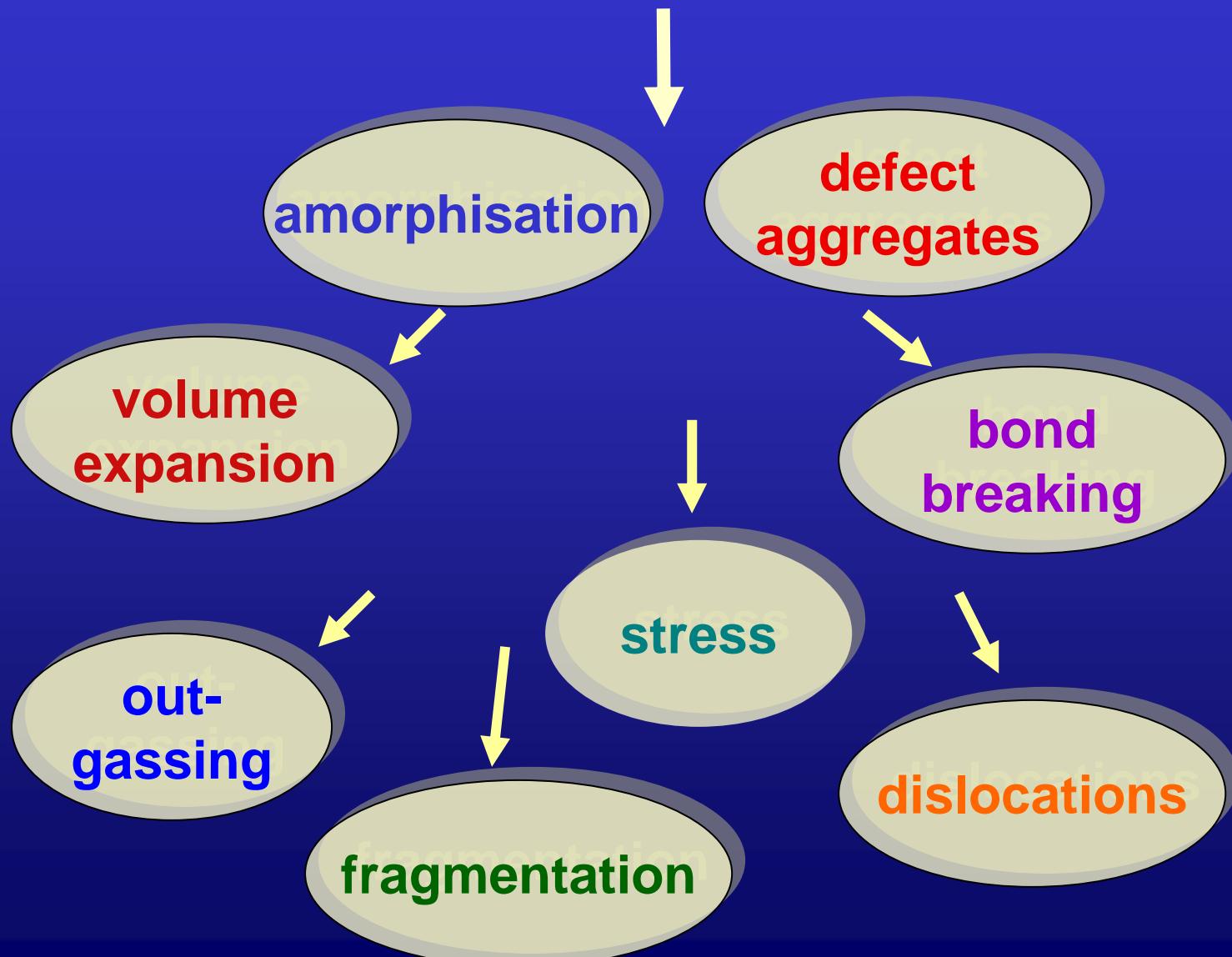
**energy**       **$\sim 0.3 E_{\text{tot}}$**

**halo (single defects)**

**radius**      **10-40 nm**

**energy**       **$\sim 0.7 E_{\text{tot}}$**

# Ion-induced bulk modifications

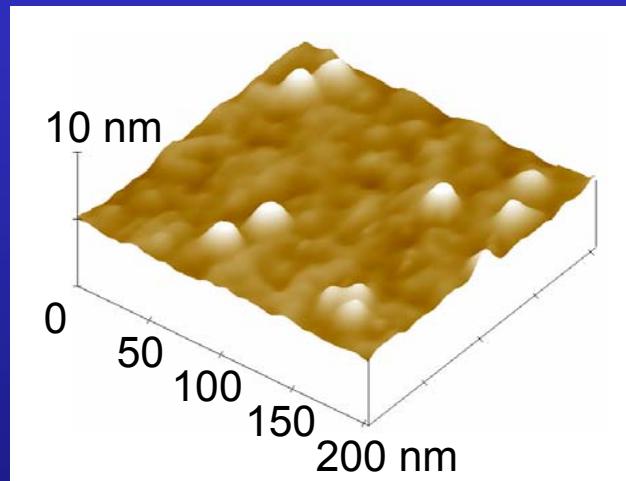


# Ion-induced surface processes

scanning force microscopy

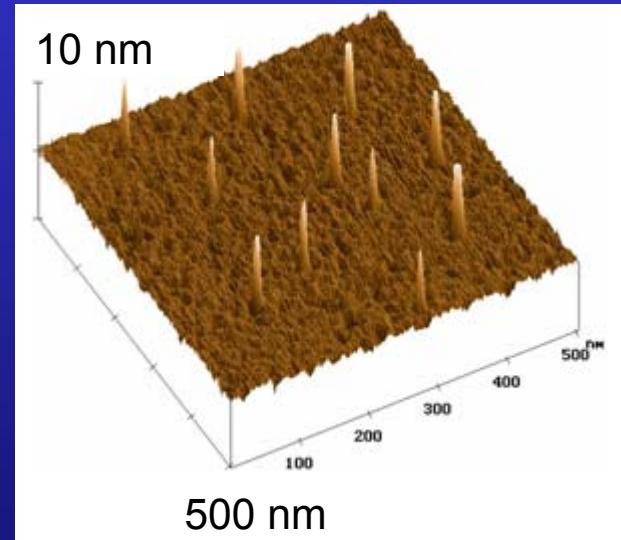
amorphous metallic alloy

$\text{Fe}_{85}\text{B}_{15}$

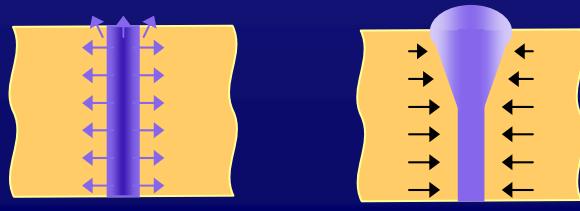


Audouard, NIMB 146 (1998)

ionic crystal  $\text{CaF}_2$

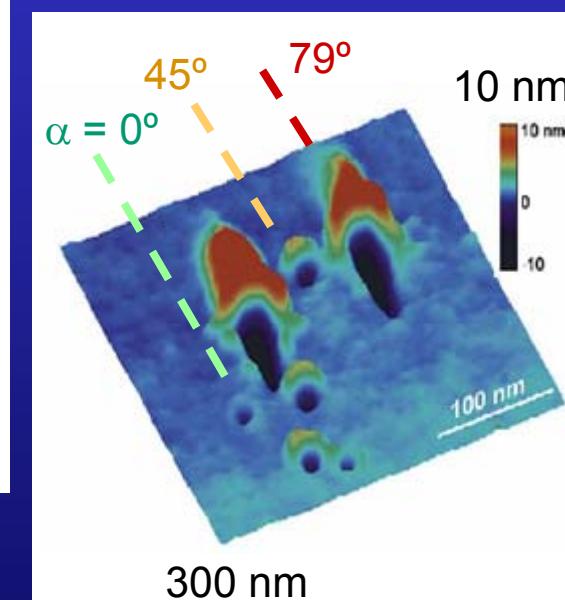


Khalfaoui NIMB (2005)



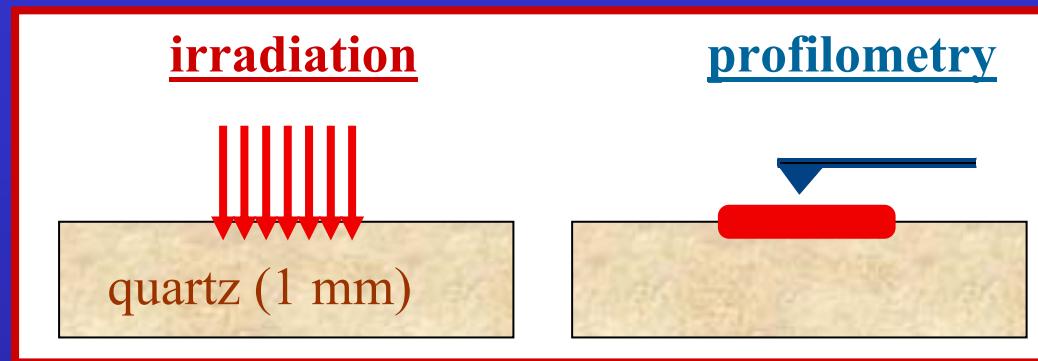
$$\rho_{\text{matrix}} > \rho_{\text{track}}$$

polymer (PMMA)

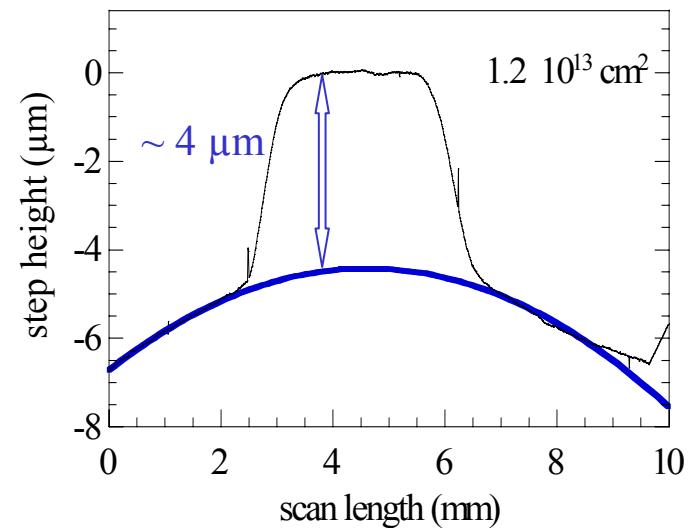
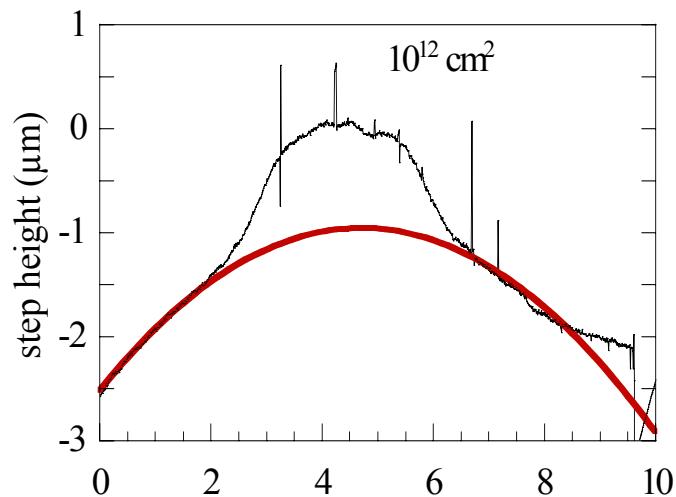


Papaléo, NIMB 206 (2001)

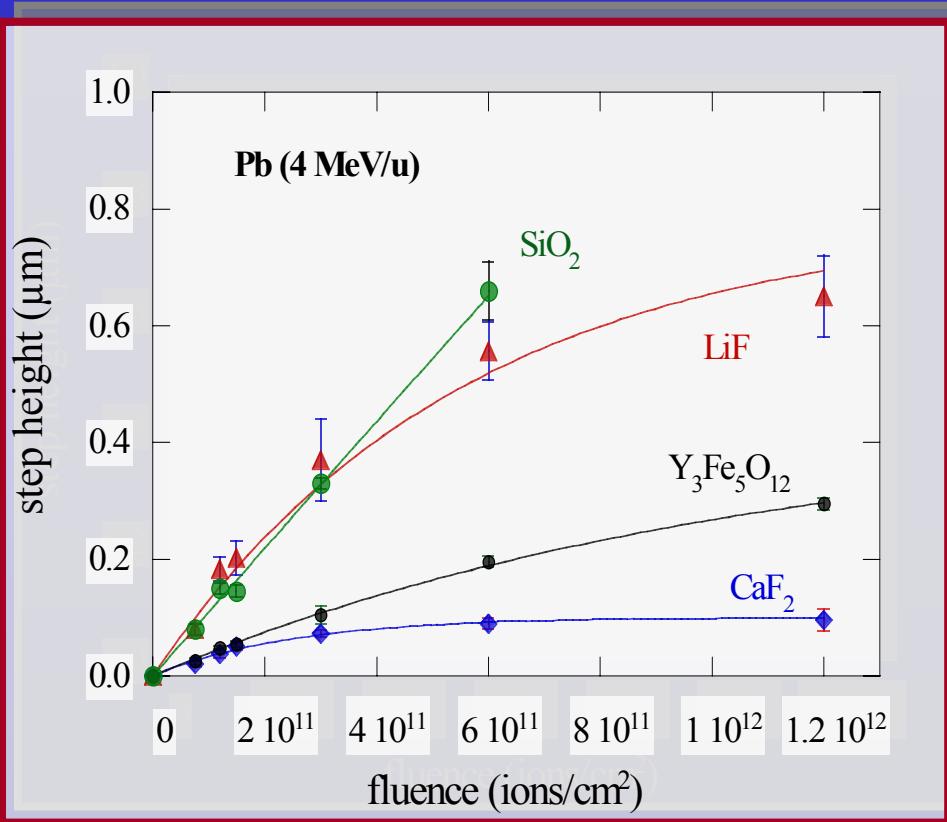
# Swelling and stress due to phase change and/or defects



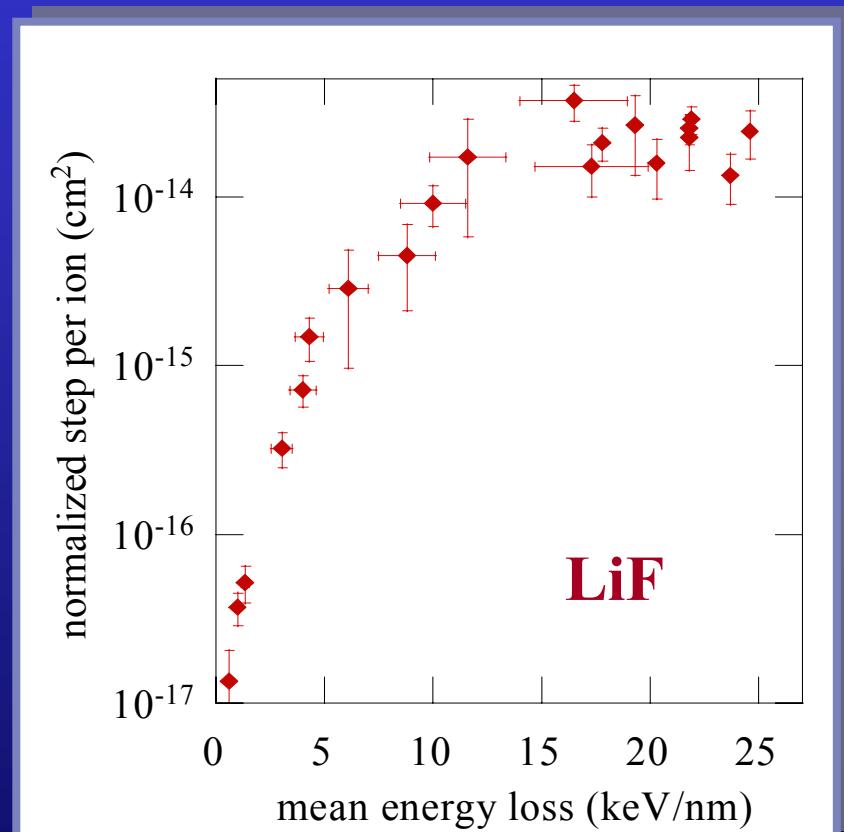
Xe (450 MeV) → quartz (range = 30 μm)



# ion-induced swelling



# threshold effect

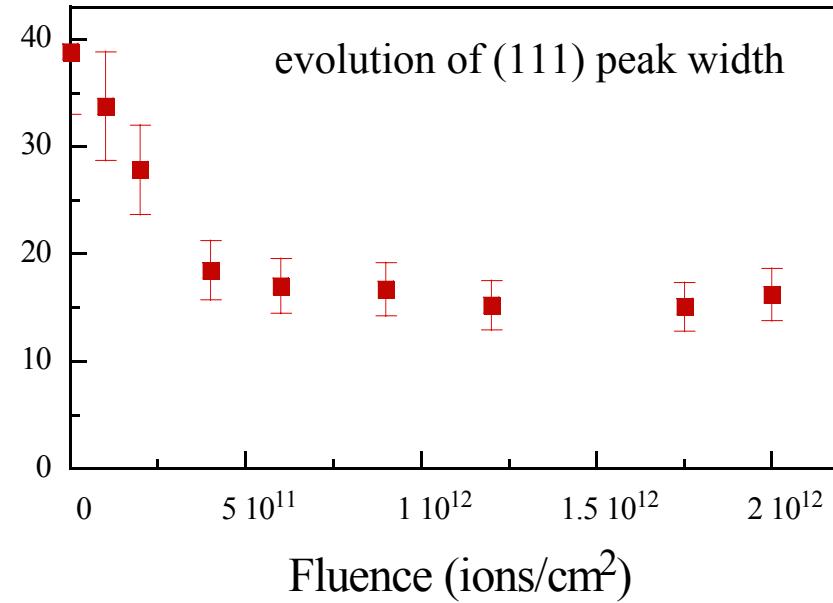


- scales with range of ions
- saturates at high fluences
- increases with electronic energy loss
- occurs above a  $dE/dx$  threshold

# Beam-induced grain breaking

**4 MeV/u Pb → CaF<sub>2</sub> powder**

in-situ X-ray diffraction

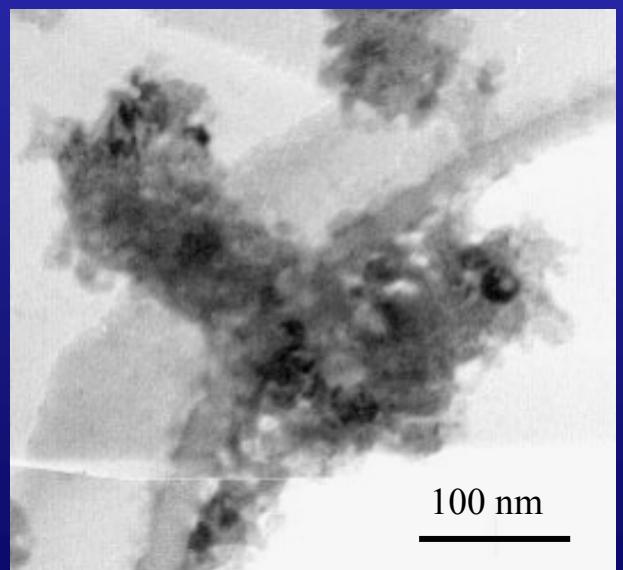


40 nm → 20 nm grains

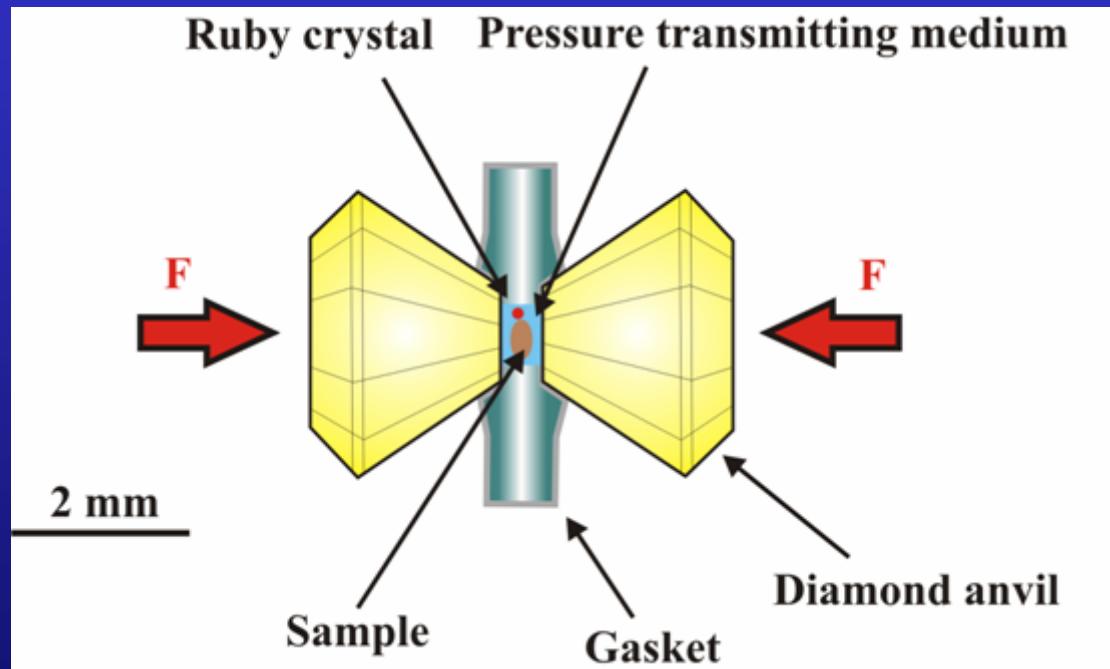
before irradiation



$10^{12} \text{ cm}^{-2}$

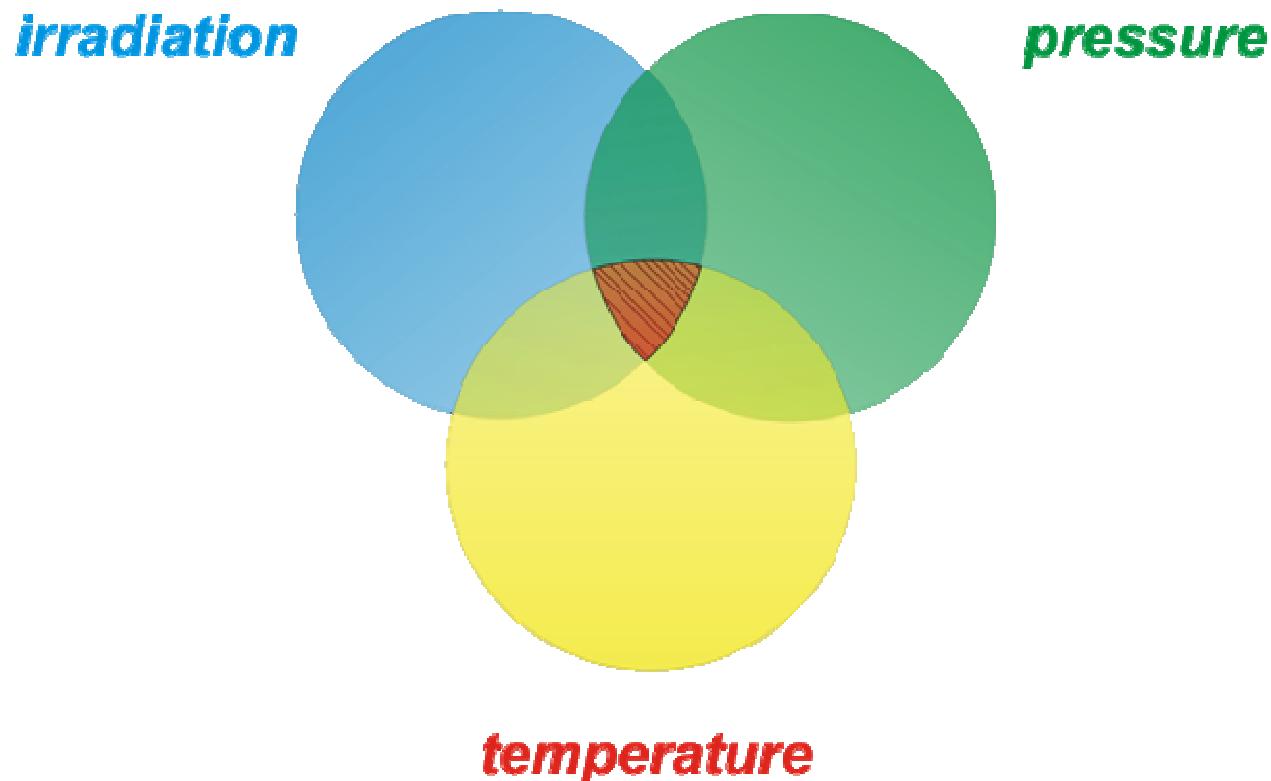


# Use of diamonds in irradiation experiments



# Solids under extreme conditions

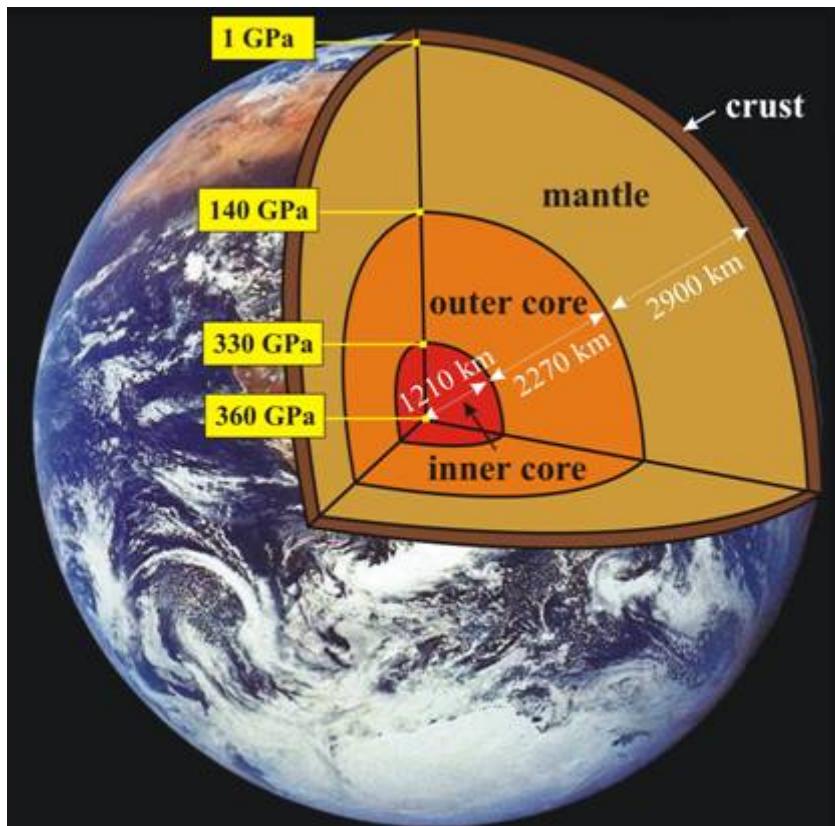
simultaneous or sequential exposure



Motivation: Materials Science & Geosciences

# Geo- and thermochronology

Minerals exposed to high pressure and temperature



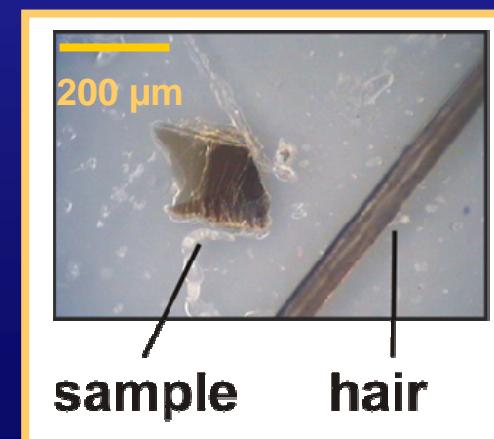
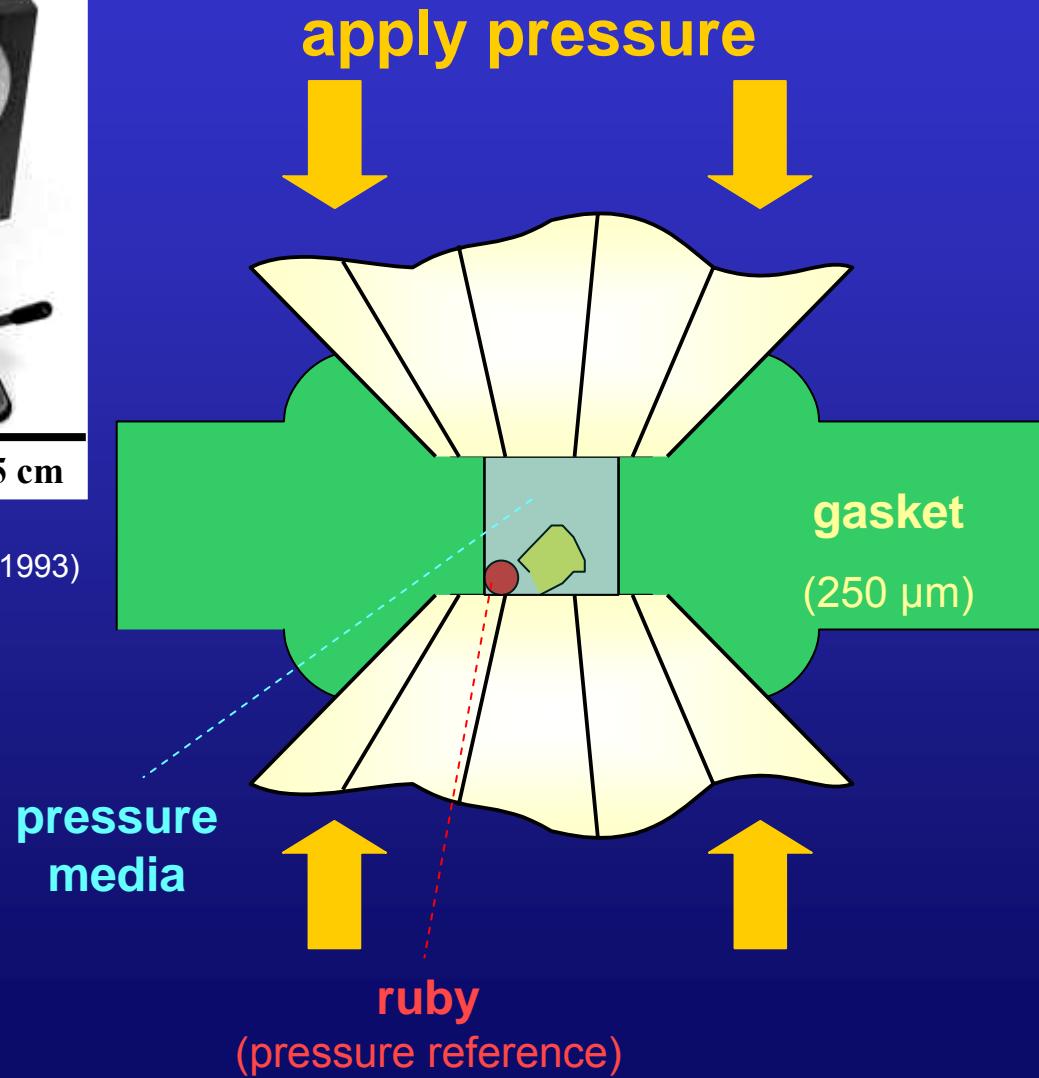
Earth's interior:  
25 °C/km and 50 MPa/km

- ★ influence of pressure on fission track formation?  
(e.g. track length → dating)
  
- ★ can fission fragments induce specific phase transitions?

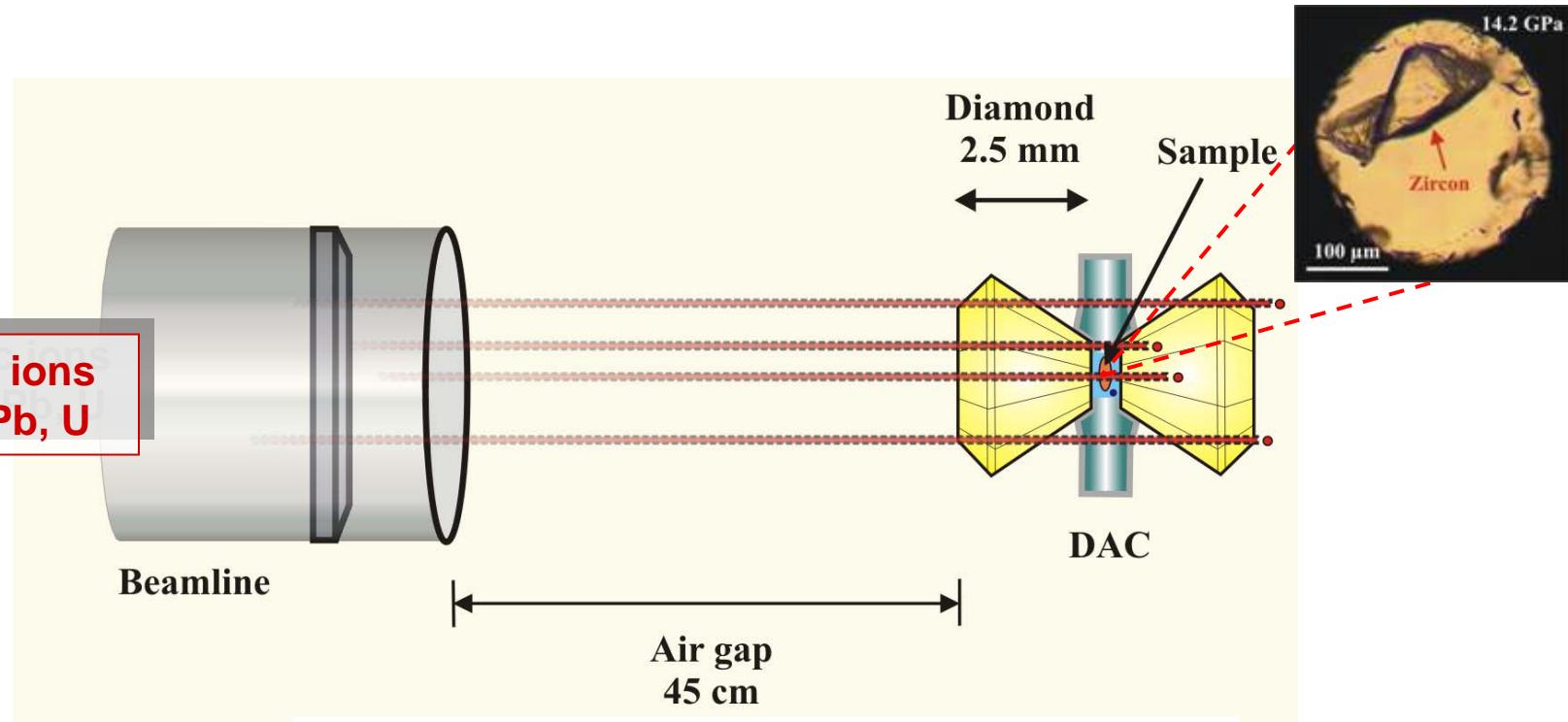
# diamond anvil cell (DAC)



Bassett et al.,  
Rev. Sci. Instrum. 64 (1993)

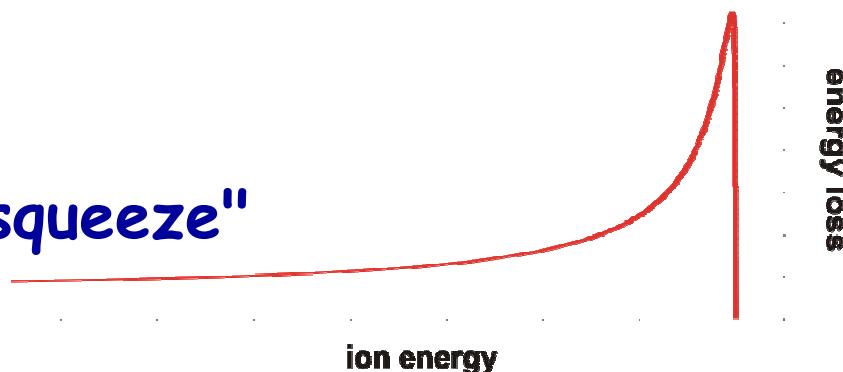


# Irradiation experiments with pressurized samples



"Heavy ions feel the squeeze"

PhysicsWeb 5/2006  
Phys. Rev. Lett. 96 (2006)



# Irradiation experiments with samples pressurized in diamond anvil cells (DAC)

relativistic ions  
(e.g., Au, Pb,

- intense photoluminescence
- pressure remained constant in cell  
(up to  $> 50$  GPa and  $5 \times 10^{12}$  ions/cm $^2$ )
- no instantaneous diamond failure

!!! but after several beamtimes:

- coloration
- risk of diamond fragmentation (stress??)

Diamond  
2.5 mm

Sample

Zircon

14.2 GPa

100  $\mu\text{m}$

45 cm

Beamline

45 cm

energy loss

ion energy

